

TECHNOLOGY CHARACTERIZATION WORKSHOP

Module 1

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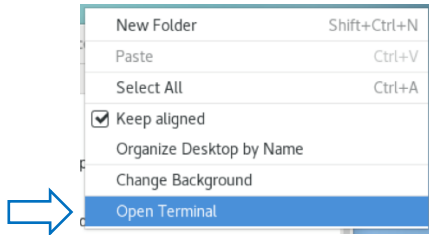
1. Revision History

Version	Date	Authors	Comments
1.0	2025/06/23	Renesas Team	Initial version

2. Create working library

2.1. Open new Mate Terminal

Right click on desktop and open a new Terminal.



2.2. Select the Project directory

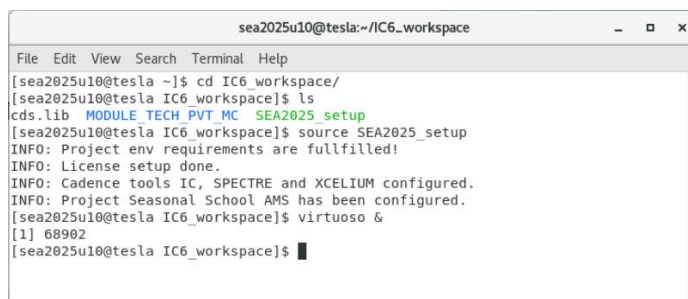
➤ `cd IC6_workspace`

2.3. Load environment variables

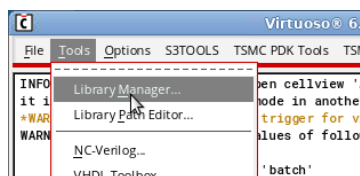
➤ `source SEA2025_setup`

2.4. Launch the Cadence Virtuoso

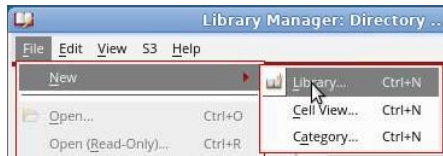
➤ `virtuoso &`



2.5. Open library manager



2.6. Create new working library



Give a suitable name to your working library (on below examples the name “*AMSdesign2025*” was used) and attach it to an existing technology library.



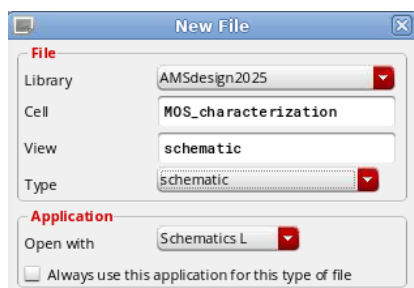
Select “*tsmcN28*” from the list and click OK.

3. MOS Parameter Characterization

3.1. Create a new schematic view



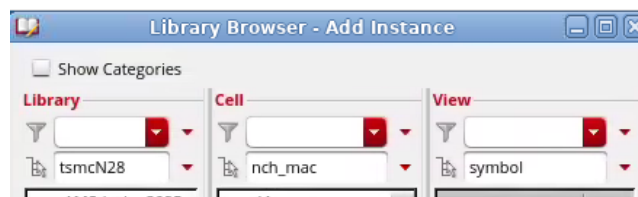
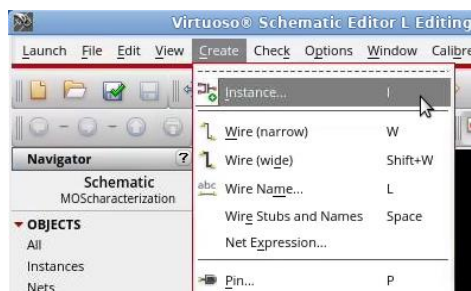
Give a suitable name to your schematic (on below examples the name “MOS_characterization” was used).



3.2. Add devices

Instance a core voltage NMOS (“nch_mac”) and PMOS (“pch_mac”), and DC voltage sources like the schematic below.

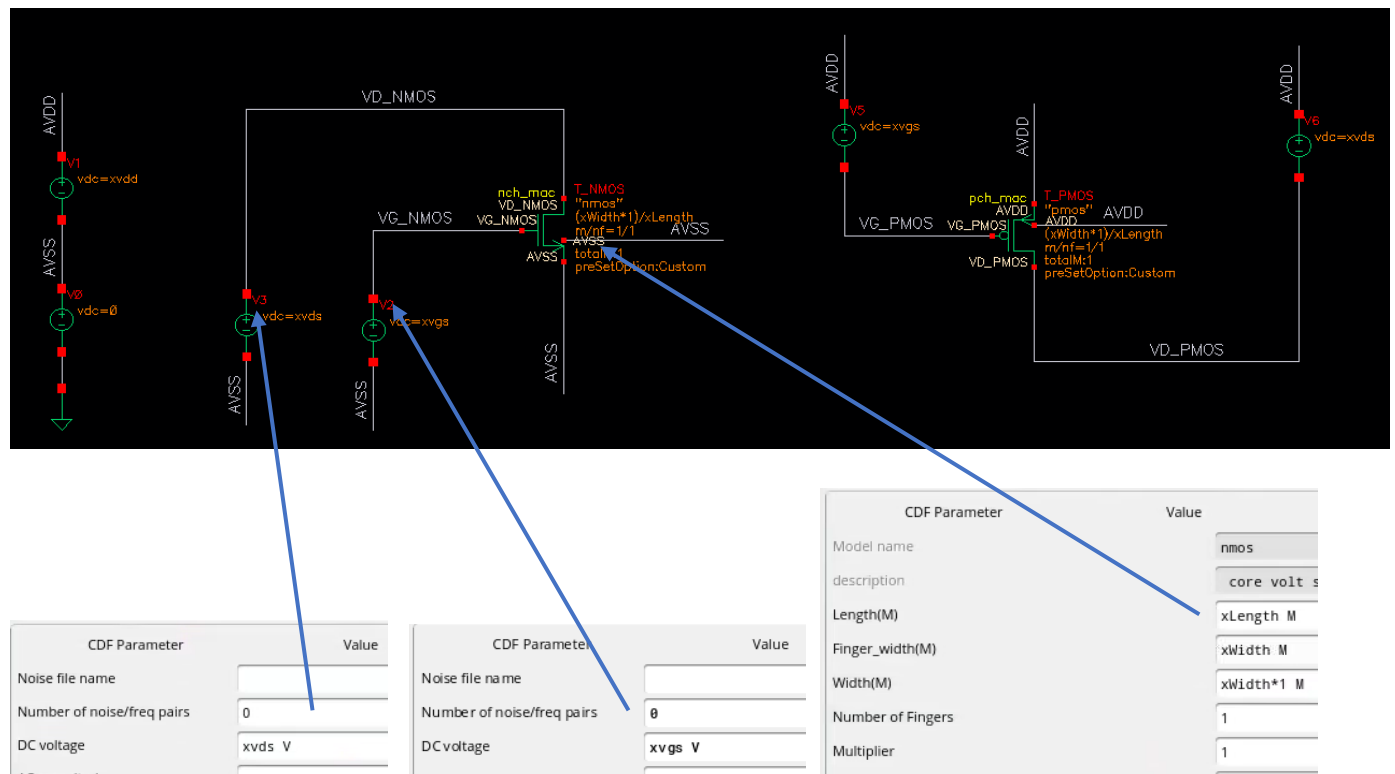
Rename the NMOS instance to “T_NMOS” and the PMOS instance to “T_PMOS”, for later use.



Instance	Library	Cell	View
NMOS	tsmcN28	nch_mac	symbol
PMOS	tsmcN28	pch_mac	symbol
DC voltage source	analogLib	vdc	symbol
ground	basic	gnd	symbol

Add variable names to DC voltages sources values, and to length and width of transistors to be used later for parameters variations. See examples below:

h



Alternatively, you can copy the following pre-edited schematic to your library:

Library	Cell	View
MODULE_TECH_PVT_MC	MOS_characterization	schematic

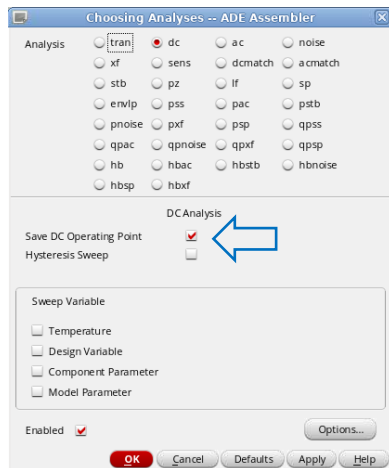
3.3. Create a new Maestro Analog Design Environment (ADE Explorer)

On schematic launch the Maestro ADE Explorer environment.

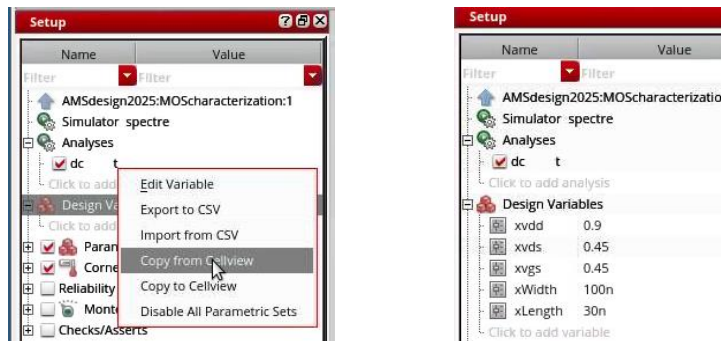


3.4. Select analysis and define variable values

Select “dc” analysis and “Save DC Operating Point” check box.

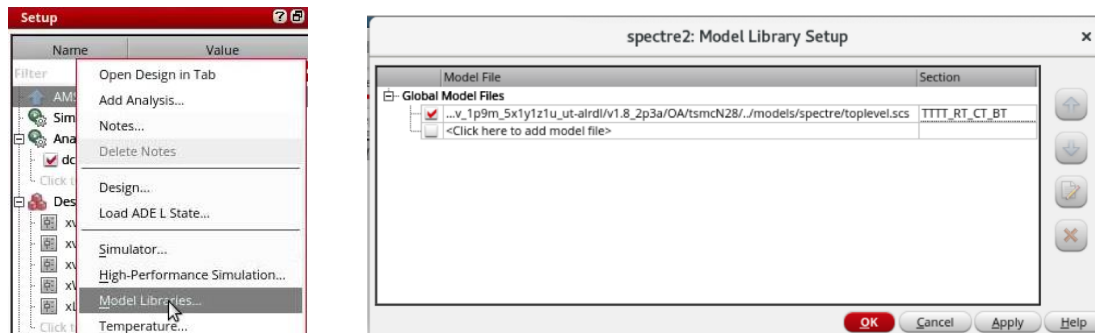


Copy variables from schematic and double click on the left side of the variable to edit their values. See example below.



3.5. Edit Model Libraries path and Corner Section

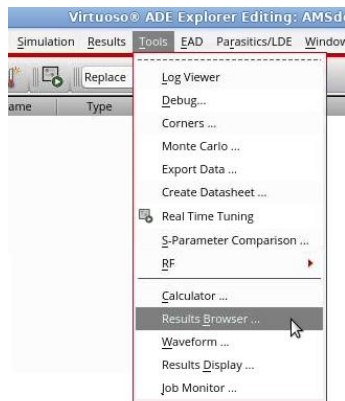
Add the below model libraries path to “Global Model Files” and select “TTTT_RT_CT_BT” as corner section:



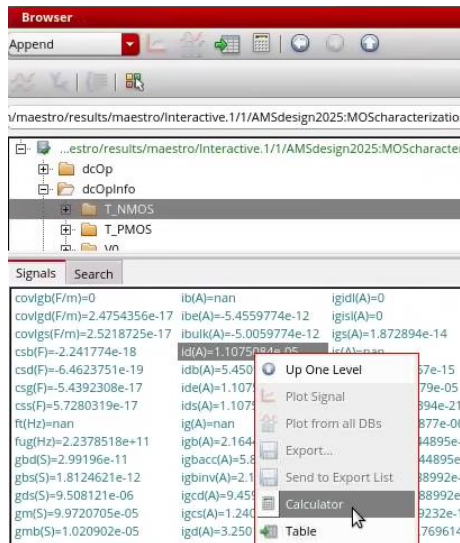
Models file path: `/DataHDD/tsmc/28n_rf_ull_hpc_plus_0p9v_1p8v_1p9m_5x1y1z1u_ut-aiirdl/v1.8_2p3a/OA/tsmcN28/./models/spectre/toplevel.scs`

3.6. Run Simulation and see results

Hit the ► to run the simulation and open the “Results Browser”.

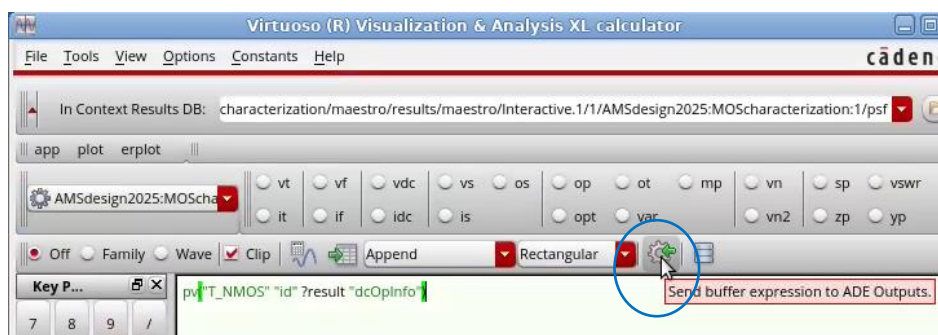


On Results Browser select one transistor DC operating point parameter and send it to calculator.



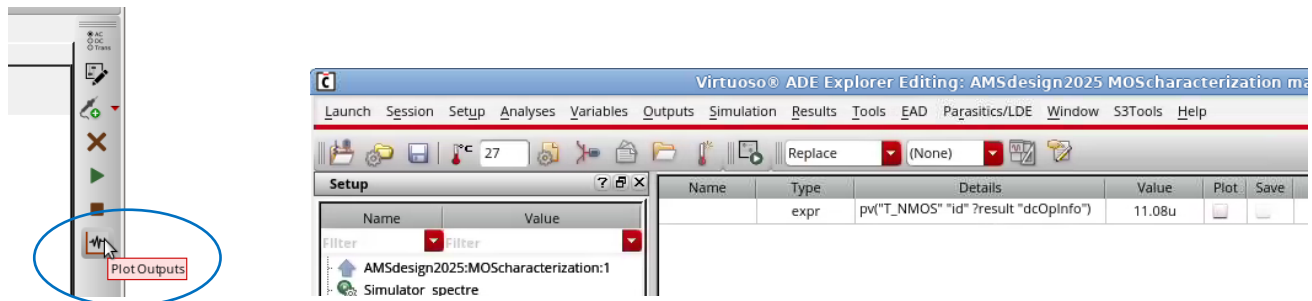
Right click over any transistor parameter value to open the dialog box

Once on calculator send it to Maestro ADE to be calculated every time the simulation is run.



Do the above steps for every parameter you want to observe.

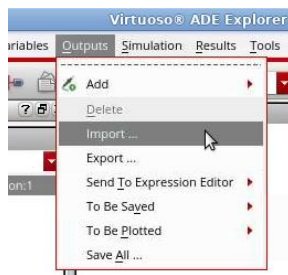
Refresh the ADE outputs plot and confirm the resulting values are matched with the results browser. See example below:



Every time a new simulation is run the saved expression will be calculated and their results plotted on ADE outputs results.

3.7. Load a pre-defined list of measurements

Import the below pre-defined measures file and refresh the ADE outputs plot.



Pre-defined measurements file path:

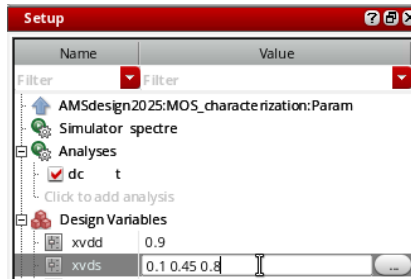
`~/IC6_workspace/MODULE_TECH_PVT_MC/
outputs_AMSdesign2025_MOS_characterization_maestro_params.csv`

Example of measured results:

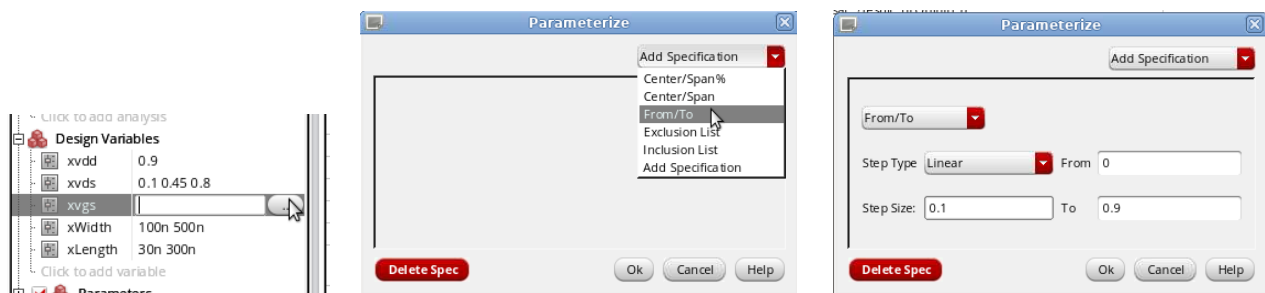
Name	Type	Details	Value	Plot
Filter	Filter	Filter	Filter	Filter
VGS	expr	$(v("VG_NMOS" ?result "dcOp") - v("AVSS" ?result "dcOp"))$	450m	✓
VDS	expr	$(v("VD_NMOS" ?result "dcOp") - v("AVSS" ?result "dcOp"))$	450m	✓
Id_NMOS	expr	$pv("T_NMOS" "id" ?result "dcOpInfo")$	11.08u	✓
GmoverId_NMOS	expr	$(pv("T_NMOS" "gm" ?result "dcOpInfo") / pv("T_NMOS" "id" ?result "dcOpInfo"))$	9.004	✓
Vdsat_NMOS	expr	$pv("T_NMOS" "vdsat" ?result "dcOpInfo")$	169.3m	✓
Vth_NMOS	expr	$pv("T_NMOS" "vth" ?result "dcOpInfo")$	390.3m	✓
Gm_NMOS	expr	$pv("T_NMOS" "gm" ?result "dcOpInfo")$	99.72u	✓
Gds_NMOS	expr	$pv("T_NMOS" "gds" ?result "dcOpInfo")$	9.508u	✓
Cgg_NMOS	expr	$pv("T_NMOS" "cgg" ?result "dcOpInfo")$	70.92a	✓
Cds_NMOS	expr	$pv("T_NMOS" "cds" ?result "dcOpInfo")$	458.6z	✓
Cgd_NMOS	expr	$pv("T_NMOS" "cgd" ?result "dcOpInfo")$	-24.87a	✓
Cgs_NMOS	expr	$pv("T_NMOS" "cgs" ?result "dcOpInfo")$	-41.79a	✓
Ig_NMOS	expr	$pv("T_NMOS" "igt" ?result "dcOpInfo")$	42.76f	✓
Id_Pmos	expr	$pv("T_PMOS" "id" ?result "dcOpInfo")$	-2.855u	✓
GmoverId_Pmos	expr	$abs((pv("T_PMOS" "gm" ?result "dcOpInfo") / pv("T_PMOS" "id" ?result "dcOpInfo")))$	15.49	✓
Vdsat_Pmos	expr	$pv("T_PMOS" "vdsat" ?result "dcOpInfo")$	-75.65m	✓
Vth_Pmos	expr	$pv("T_PMOS" "vth" ?result "dcOpInfo")$	-442.6m	✓
Gm_Pmos	expr	$pv("T_PMOS" "gm" ?result "dcOpInfo")$	44.22u	✓
Gds_Pmos	expr	$pv("T_PMOS" "gds" ?result "dcOpInfo")$	5.491u	✓
Cgg_Pmos	expr	$pv("T_PMOS" "cgg" ?result "dcOpInfo")$	74.95a	✓
Cds_Pmos	expr	$pv("T_PMOS" "cds" ?result "dcOpInfo")$	61.63z	✓
Cgd_Pmos	expr	$pv("T_PMOS" "cgd" ?result "dcOpInfo")$	-25.19a	✓
Cgs_Pmos	expr	$pv("T_PMOS" "cgs" ?result "dcOpInfo")$	-46.06a	✓
Ig_Pmos	expr	$pv("T_PMOS" "igt" ?result "dcOpInfo")$	-64.96f	✓

3.8. Add transistors parameters variations

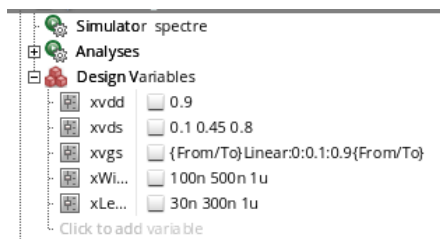
On ADE setup environment add more than one value to variables to enable the parametric simulations. ADE will cross all the values independently and run a simulation for each possible combination. See examples below:



Add values directly to dialog box separated by spaces like the example on the left or open the “Parameterize” box as the example below.



Example of parametric variables variations within accepted devices sizes and operating voltages:



See below an example of simulation results table. Please note, for a broader visualization, the table has been presented on “Detail - Transpose” format.

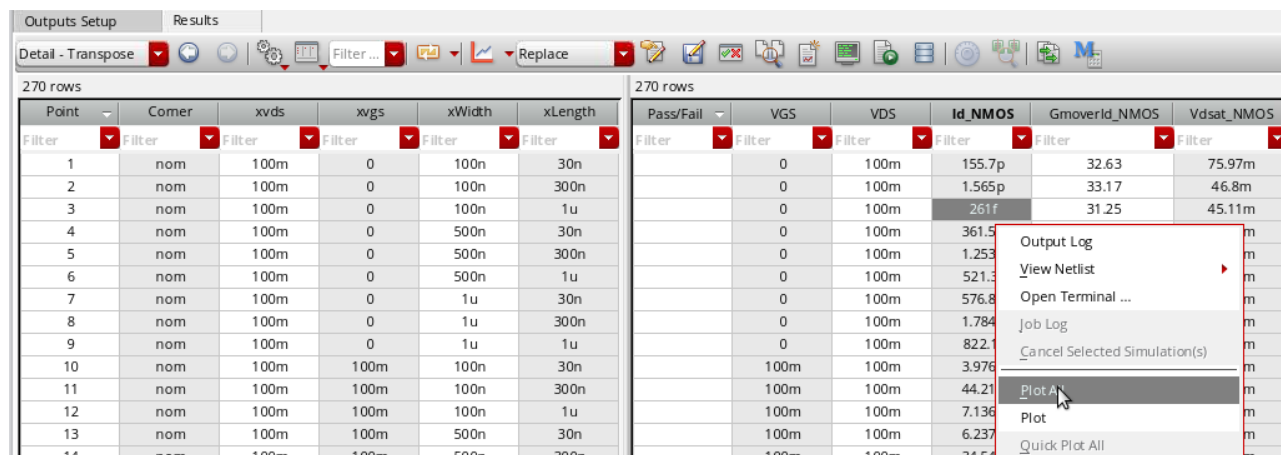
Outputs Setup

Results

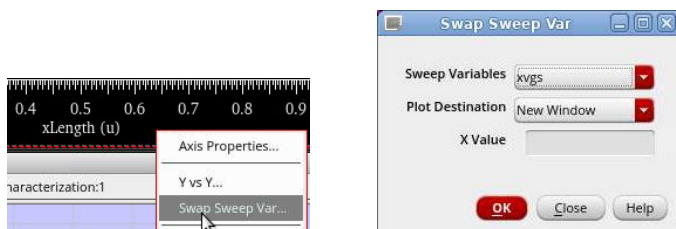
Detail - Transpose



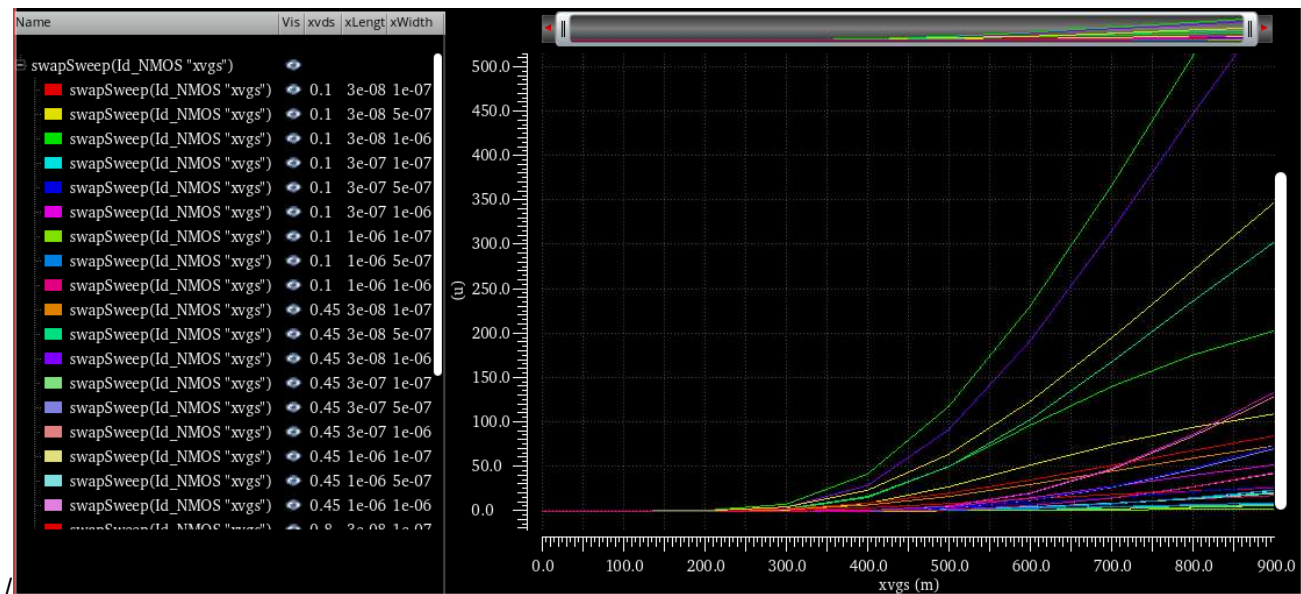
To plot all the results of a measured parameter right click on one of the results and select “Plot All”.



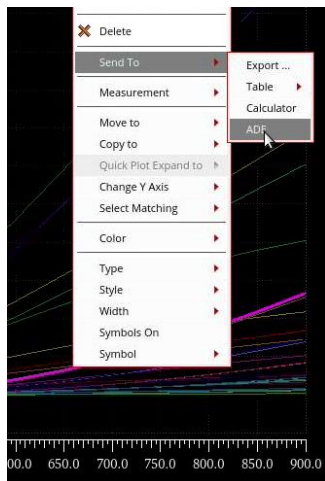
Please note, if X axis on plotted waveform is not Vgs voltage, change it by right click on the X axis and select “Swap Sweep Var” dialog box and change it to “xvgs” variable.



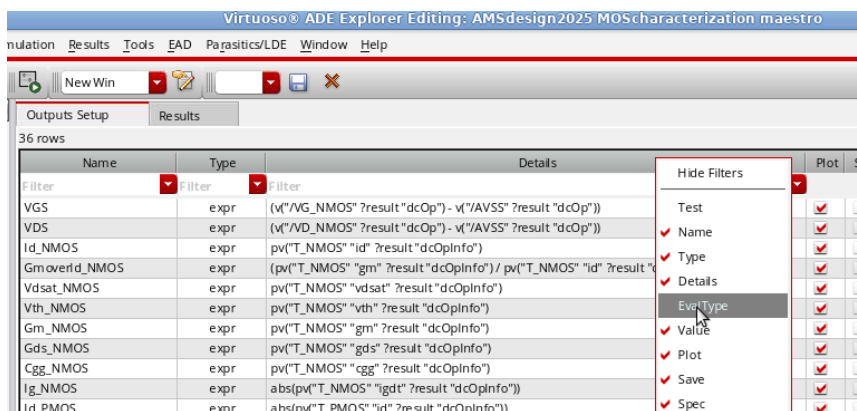
See a plot example below for NMOS drain current (vs) Vgs voltage simulation results for the different parametric values.



Plotted signals can be added to ADE by right click on a waveform → Send To → ADE. See the example below:



On ADE right click on the Details tab and make the “EvalType” column visible:



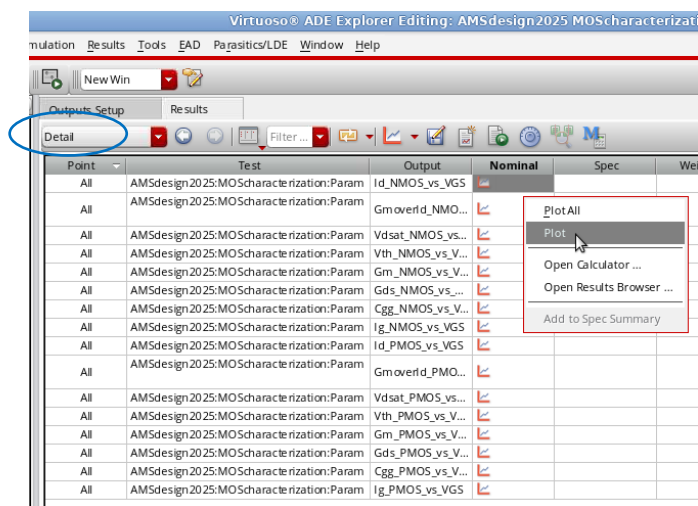
Double click on the “EvalType” box and change it from “point” to “Sweeps” to enable the post processing of the plots after all parametric simulations have been concluded for a correct plotting of results and refresh the results table. A more user-friendly name can be given to the plot. See some examples below:

Outputs Setup		Results					
35 rows							
Name		Type	Details		EvalType	Plot	Save
Filter		Filter	Filter		Filter		
Id_NMOS_vs_VGS		expr	swapSweep(Id_NMOS "xvgs")		sweeps	☒	☐
Gm overId_NMOS_vs_VGS		expr	swapSweep(Gm overId_NMOS "xvgs")		sweeps	☒	☐
Vdsat_NMOS_vs_VGS		expr	swapSweep(Vdsat_NMOS "xvgs")		sweeps	☒	☐
Vth_NMOS_vs_VGS		expr	swapSweep(Vth_NMOS "xvgs")		sweeps	☒	☐
Gm_NMOS_vs_VGS		expr	swapSweep(Gm_NMOS "xvgs")		sweeps	☒	☐
Gds_NMOS_vs_VGS		expr	swapSweep(Gds_NMOS "xvgs")		sweeps	☒	☐
Cgg_NMOS_vs_VGS		expr	swapSweep(Cgg_NMOS "xvgs")		sweeps	☒	☐
Ig_NMOS_vs_VGS		expr	swapSweep(Ig_NMOS "xvgs")		sweeps	☒	☐
Id_PMOVS_vs_VGS		expr	swapSweep(Id_PMOVS "xvgs")		sweeps	☒	☐
Gm overId_PMOVS_vs_VGS		expr	swapSweep(Gm overId_PMOVS "xvgs")		sweeps	☒	☐
Vdsat_PMOVS_vs_VGS		expr	swapSweep(Vdsat_PMOVS "xvgs")		sweeps	☒	☐
Vth_PMOVS_vs_VGS		expr	swapSweep(Vth_PMOVS "xvgs")		sweeps	☒	☐

Alternatively, you can import the following pre-defined plots file:

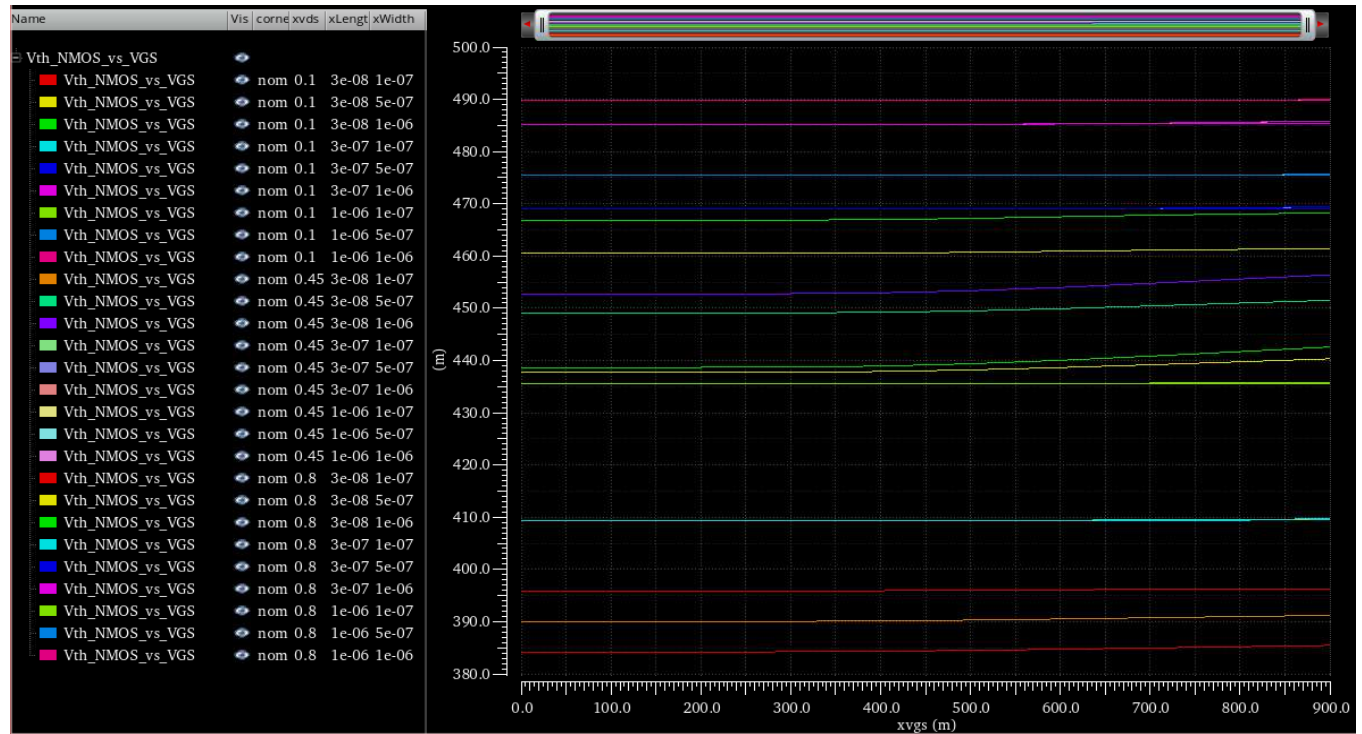
~\IC6_workspace / MODULE_Tech_PVT_MC / outputs_AMSdesign2025_MOS_characterization_maestro_plots.csv

To plot the above expressions, change the visualization of results on ADE to “Detail” and plot the waveforms with right click on a result waveform icon, and then on Plot.

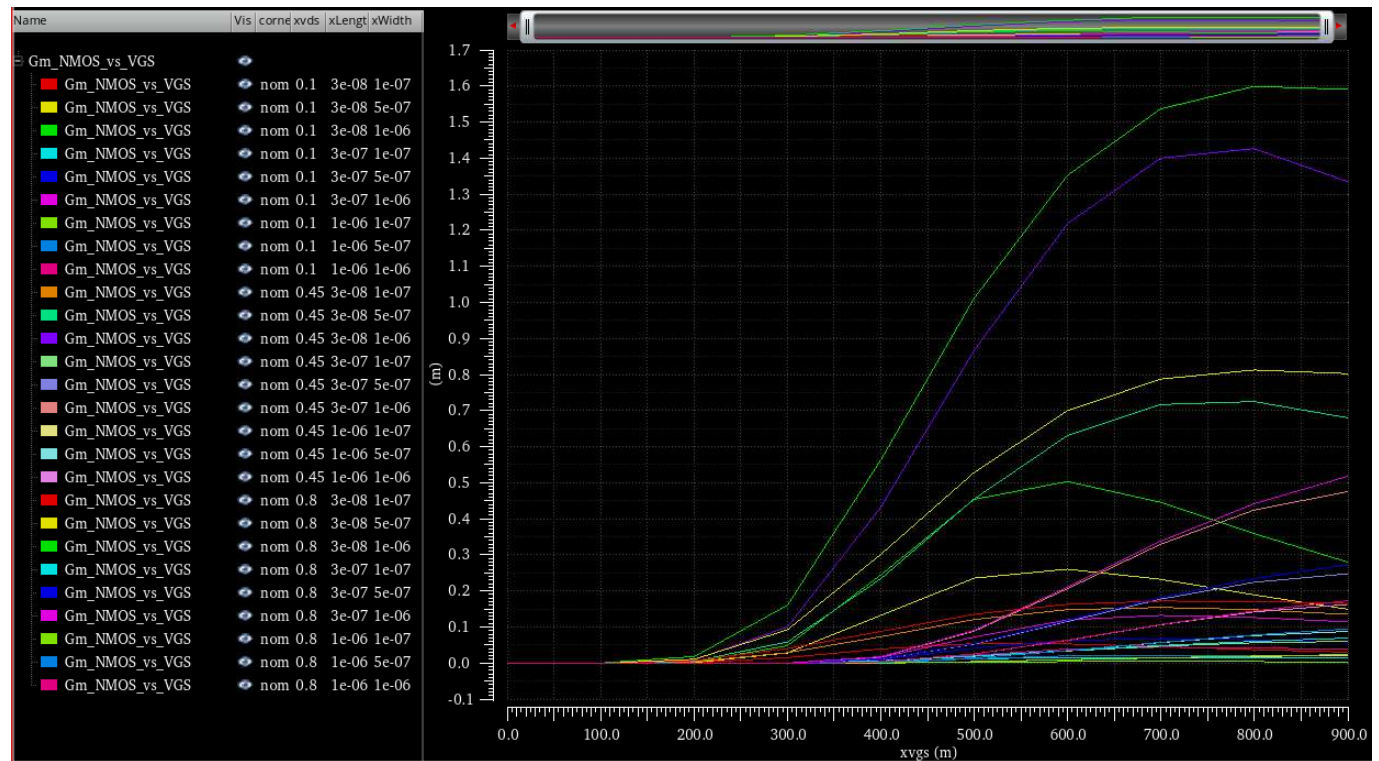


Example of plots from ADE expression simulation results table:

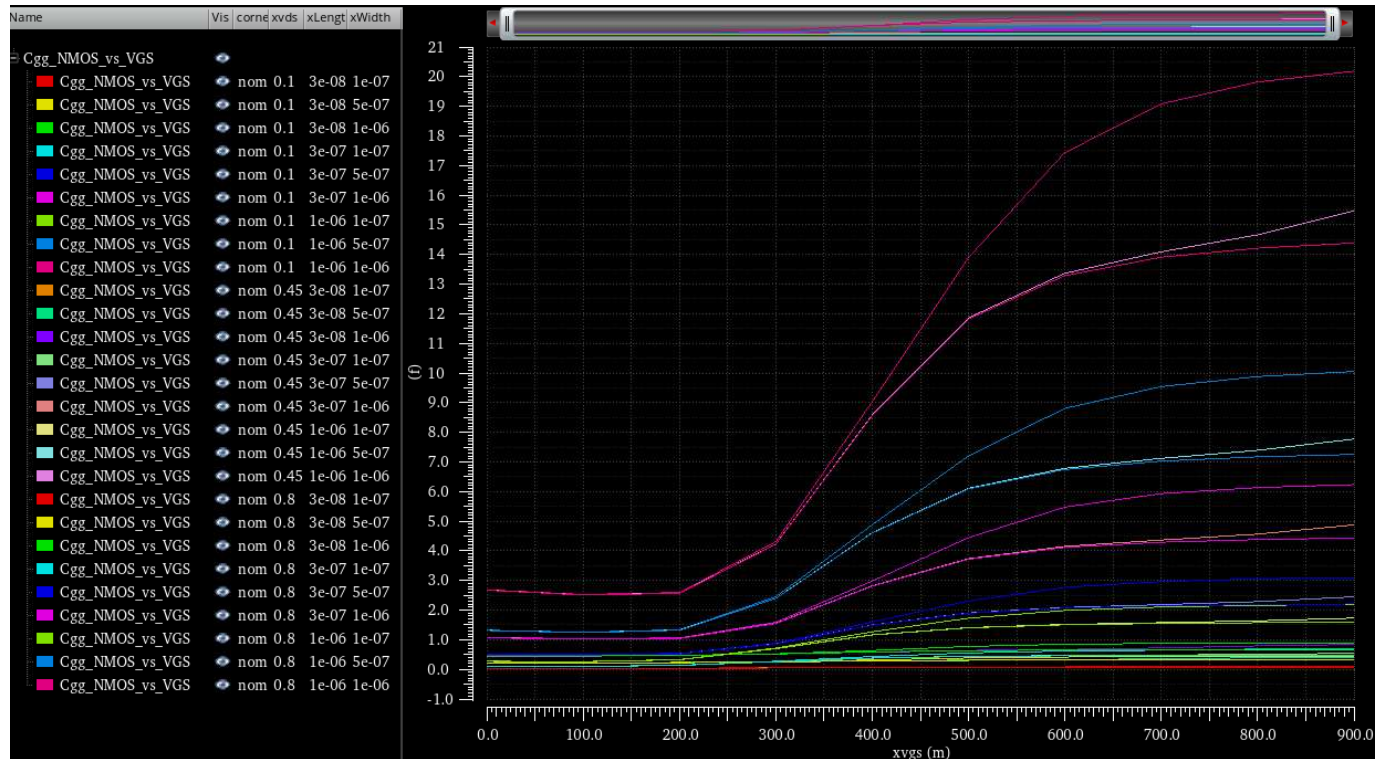
- NMOS V_{th} (vs) V_{gs} (Threshold voltage vs gate to source differential voltage)



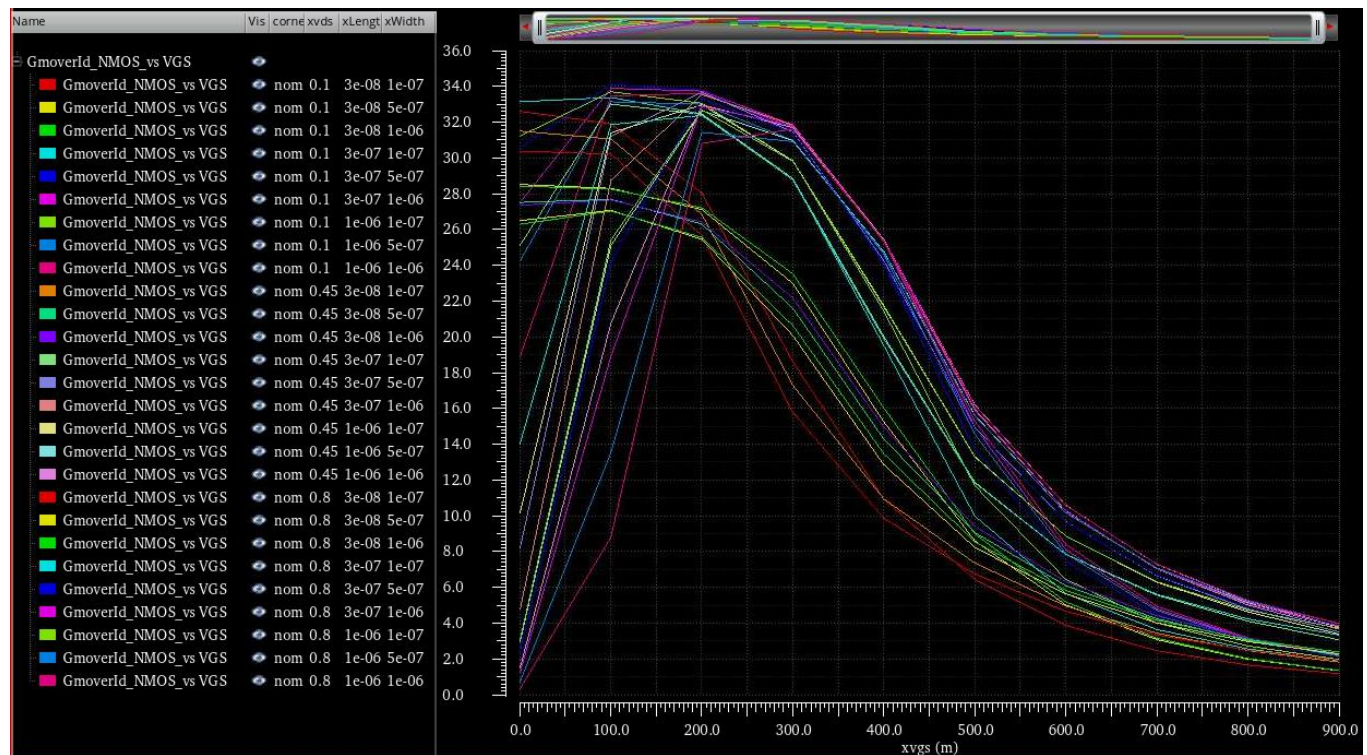
- NMOS G_m (vs) V_{gs} (Transconductance vs gate to source differential voltage)



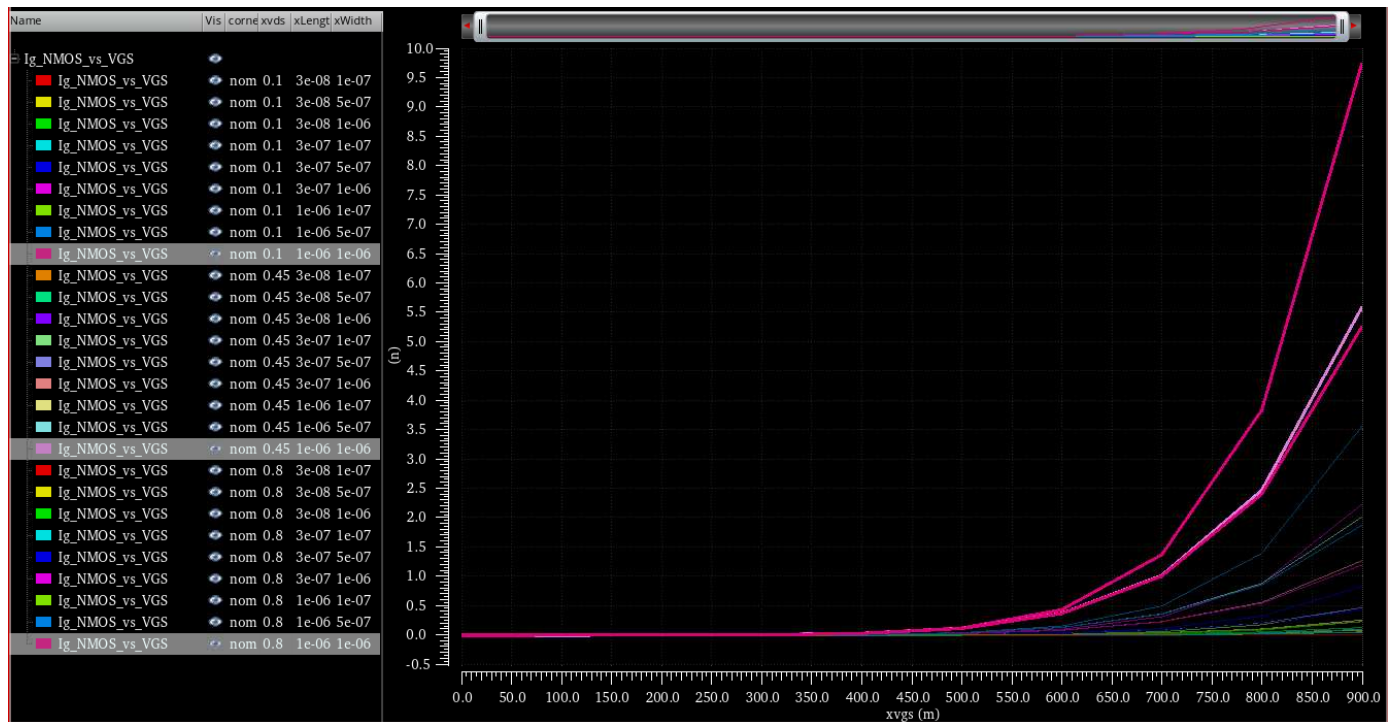
- NMOS C_{gg} (vs) V_{gs} (Total gate capacitance vs gate to source differential voltage)



- NMOS G_m/I_d (vs) V_{gs} (Transconductance Efficiency vs gate to source differential voltage)

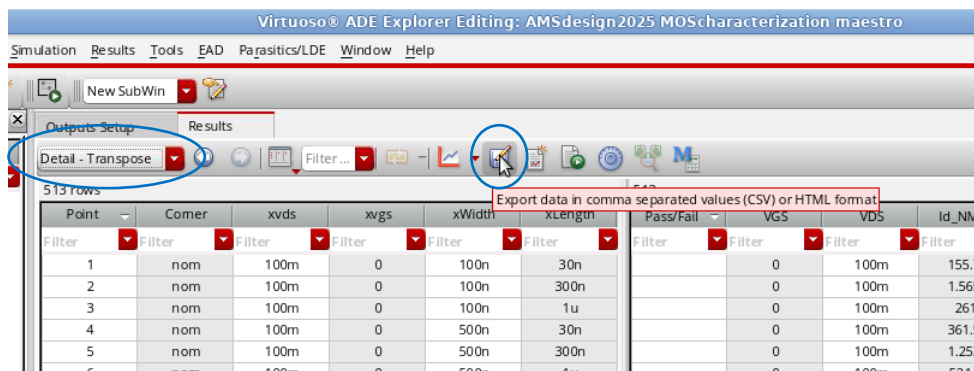


- NMOS I_g (vs) V_{gs} (gate leakage vs gate to source differential voltage)

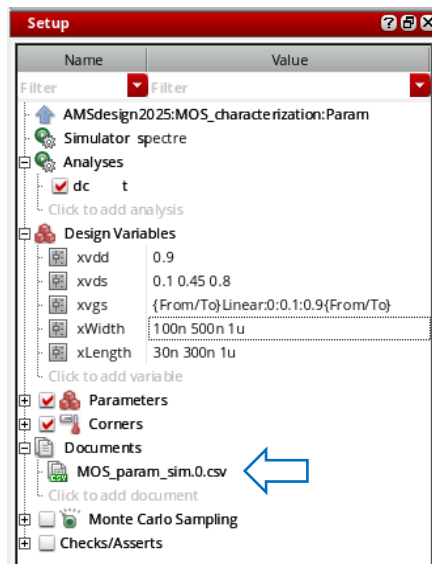


3.9. Save results to CSV file

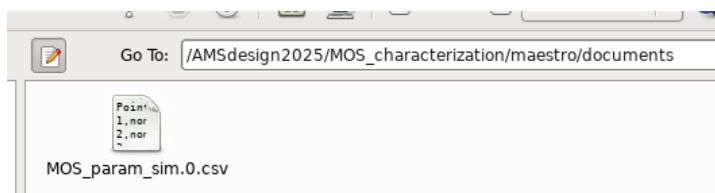
Simulation measured results can be saved on CSV file for post-simulation editing using for example Matlab, Excel, Octave, etc.



The saved CSV file can be accessed directly from the Maestro ADE on “Documents” tab.



Or alternatively through the file explorer on the following location:

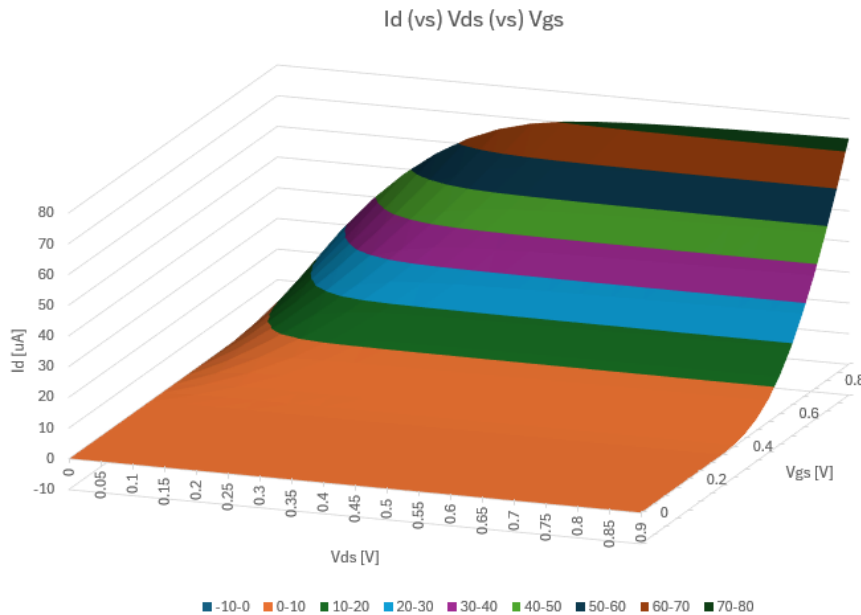


<Library name> / <Testbench schematic design name> / maestro / documents / <csv filename>

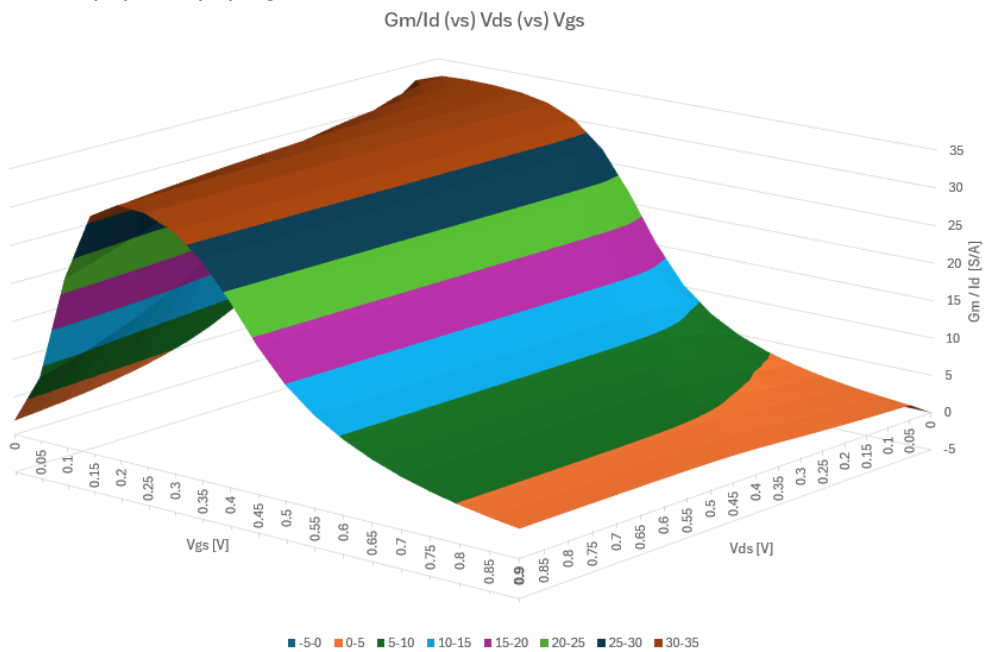
3.10. Example of post processing CSV data

On the example below the I_d and G_m/I_d of a NMOS transistor has been measured with a sweep of V_{ds} and V_{gs} voltages on the range [0V ; 0.9V] in steps of 50mV independently. Results have been saved to CSV format, copied to Excel tool and the following 3D plots have been generated.

- I_d (vs) V_{ds} (vs) V_{gs}



- G_m / I_d (vs) V_{ds} (vs) V_{gs}



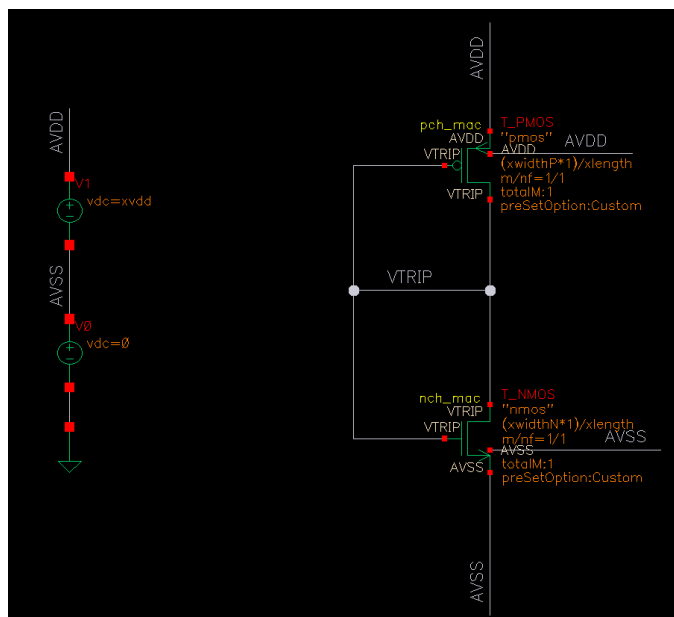
4. Diode connected inverter

4.1. Schematic

Copy the Diode Connected Inverter schematic from reference library.

Library	Cell	View
MODULE_TECH_PVT_MC	Dio_con_Inverter	schematic

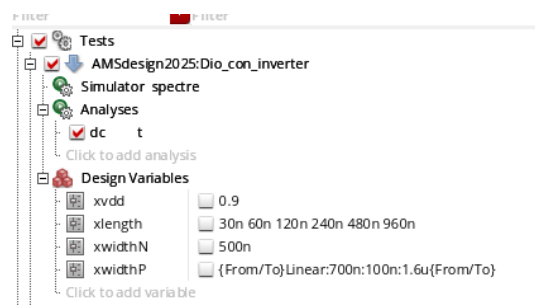
The objective of this testbench is to measure the VTRIP voltage and transistors “dc operating point” results for different lengths and widths.



4.2. Maestro ADE simulation environment

Create a new Maestro ADE simulation environment. Configure the model's library and select “TTTT_RT_CT_BT” section.

Select “dc” simulation and “Save DC Operating Point” check box (if necessary, revisit point 3 above for more details). Edit the devices variables as below example:



Please note: the Width of NMOS has been kept stable to reduce the number of simulation iterations.

Import the following pre-defined measures file:

~\IC6_workspace / MODULE_TECH_PVT_MC / outputs_AMSdesign2025_Dio_con_Inverter_maestro.csv

The Maestro ADE should be like the example below:

Outputs Setup

Results

A spec has been set to V_VTRIP measurement to better identify the transistors sizes that are closer to the desired $V_{VTRIP} = AVDD / 2 = 450\text{mV}$ (all results within a margin of $450 \pm 5\text{mV}$ will appear as green color).

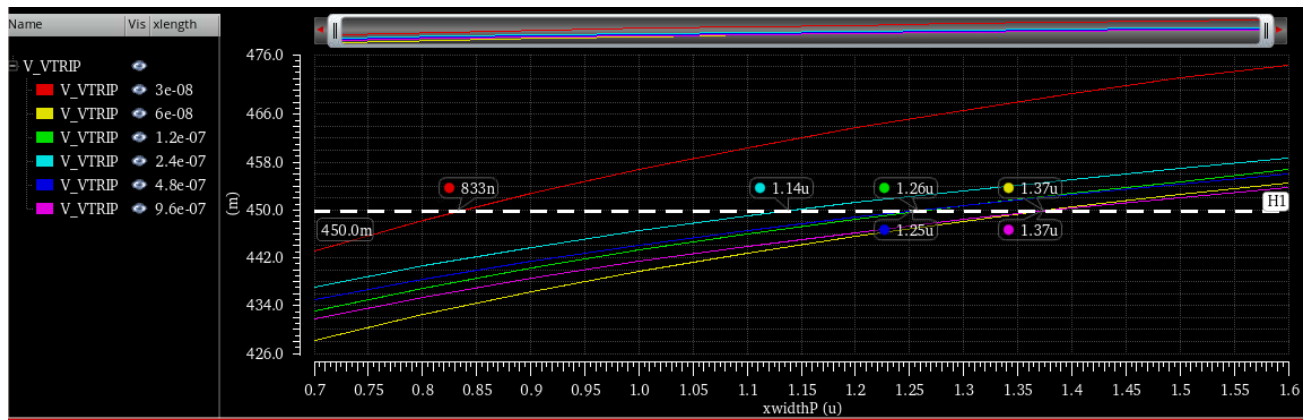
4.3. Simulation results

Run the nominal simulation. See below example of simulation results:

Point	Corner	xlength	xwidthP	Pass/Fail	Id_NMOS	Vgs_NMOS	Vth_NMOS	Vds_NMOS	Vdsat_NMOS	Cds_NMOS	Cgd_NMOS	Cgs_NMOS	Cgg_NMOS	gds
1	nom	30n	700n	near	28.26u	443.3m	449.6m	443.3m	122.4m	728.2z	-106.7a	-194.4a	316.6a	3
2	nom	30n	800n	pass	30.11u	448.5m	449.5m	448.5m	125m	746z	-106.7a	-195.5a	317.8a	3
3	nom	30n	900n	pass	31.79u	453m	449.3m	453m	127.3m	761.8z	-106.7a	-196.5a	318.7a	3
4	nom	30n	1u	near	33.32u	457m	449.2m	457m	129.3m	775.9z	-106.7a	-197.4a	319.6a	3
5	nom	30n	1.1u	near	34.73u	460.6m	449.1m	460.6m	131.2m	788.6z	-106.7a	-198.1a	320.3a	3
6	nom	30n	1.2u	near	36.06u	463.9m	449m	463.9m	132.9m	800.4z	-106.7a	-198.8a	321a	3
7	nom	30n	1.3u	near	37.27u	466.9m	448.9m	466.9m	134.4m	811.1z	-106.7a	-199.4a	321.6a	3
8	nom	30n	1.4u	near	38.43u	469.7m	448.9m	469.7m	135.9m	821.1z	-106.7a	-199.9a	322.1a	3
9	nom	30n	1.5u	near	39.51u	472.2m	448.8m	472.2m	137.2m	830.4z	-106.7a	-200.4a	322.6a	3
10	nom	30n	1.6u	near	40.45u	474.4m	448.7m	474.4m	138.3m	838.4z	-106.7a	-200.8a	323a	3
11	nom	60n	700n	near	11.57u	428.3m	457.4m	428.3m	112.3m	1.498a	-109.1a	-281.7a	421.8a	8
12	nom	60n	800n	near	12.38u	432.7m	457.3m	432.7m	114.3m	1.532a	-109.2a	-284.2a	424.2a	9
13	nom	60n	900n	near	13.12u	436.5m	457.3m	436.5m	116.2m	1.562a	-109.2a	-286.3a	426.3a	9
14	nom	60n	1u	near	13.81u	439.9m	457.3m	439.9m	117.9m	1.588a	-109.2a	-288.2a	428a	9
15	nom	60n	1.1u	near	14.44u	443m	457.3m	443m	119.4m	1.613a	-109.2a	-289.8a	429.6a	11
16	nom	60n	1.2u	pass	15.03u	445.7m	457.3m	445.7m	120.8m	1.635a	-109.2a	-291.2a	431a	1
17	nom	60n	1.3u	pass	15.59u	448.3m	457.3m	448.3m	122.1m	1.655a	-109.2a	-292.5a	432.2a	11
18	nom	60n	1.4u	pass	16.11u	450.6m	457.3m	450.6m	123.3m	1.674a	-109.3a	-293.7a	433.4a	1
19	nom	60n	1.5u	pass	16.6u	452.8m	457.3m	452.8m	124.5m	1.691a	-109.3a	-294.7a	434.4a	1
20	nom	60n	1.6u	pass	17.05u	454.7m	457.3m	454.7m	125.5m	1.707a	-109.3a	-295.6a	435.3a	1
21	nom	120n	700n	near	4.894u	433.2m	453.2m	433.2m	91.21m	2.324a	-109.8a	-625.8a	771.5a	1
22	nom	120n	800n	near	5.25u	437.1m	453.2m	437.1m	93.06m	2.345a	-109.8a	-632.1a	777.1a	1
23	nom	120n	900n	near	5.574u	440.5m	453.2m	440.5m	94.69m	2.363a	-109.8a	-637.4a	781.8a	1
24	nom	120n	1u	near	5.872u	443.5m	453.2m	443.5m	96.17m	2.378a	-109.9a	-642a	785.8a	2
25	nom	120n	1.1u	pass	6.15u	446.3m	453.2m	446.3m	97.52m	2.391a	-109.9a	-646a	789.4a	2

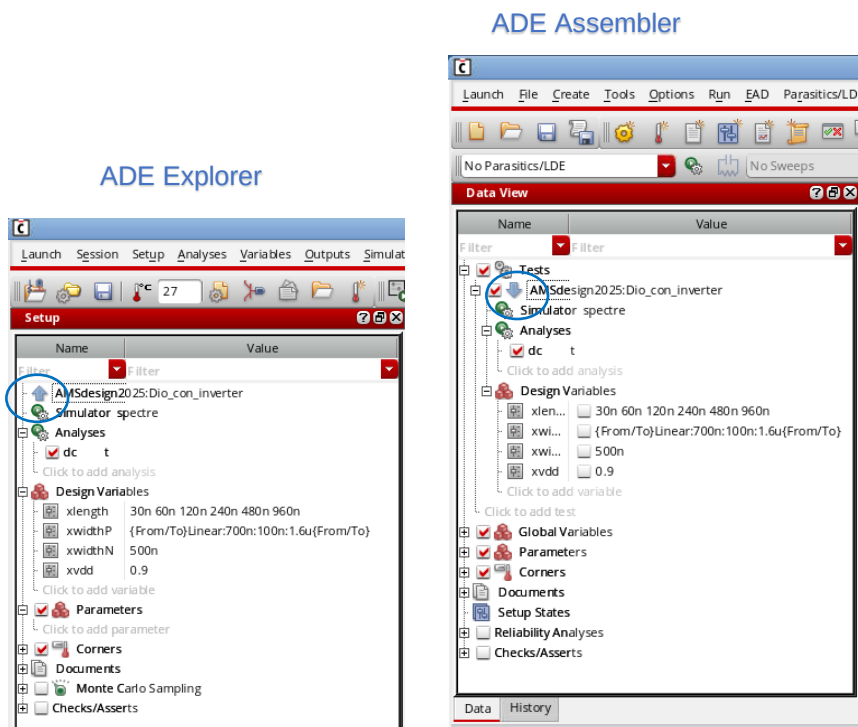
Simulation results can be saved on CSV file for future editing with other tools like Matlab, Octave, Excel, etc.

V_VTRIP results can be plotted and the variation of this voltage analyzed for the different transistors sizes combinations. See example below.



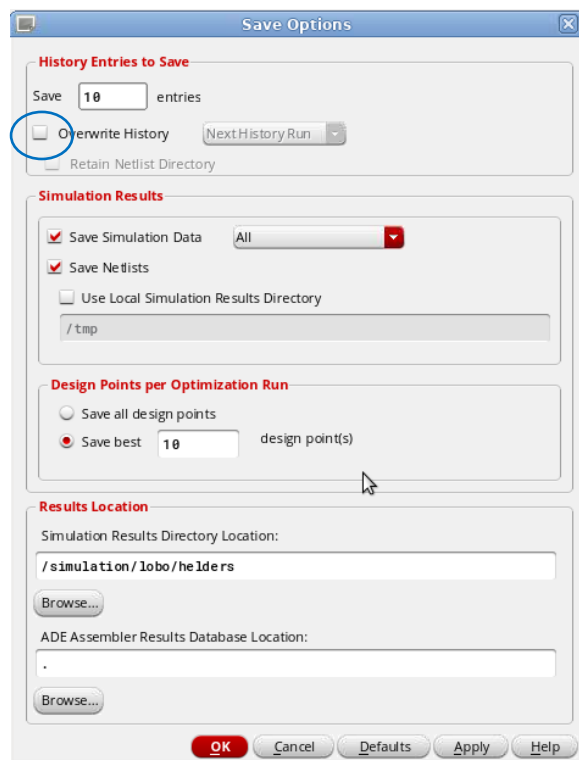
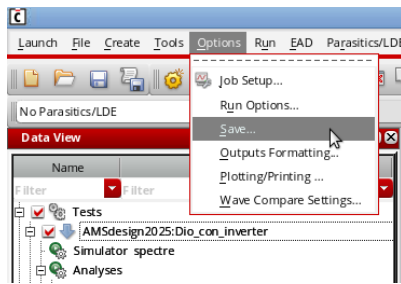
4.4. Switch from ADE Explorer to ADE Assembler (and vice versa)

Click on the  to switch from ADE explorer to ADE Assembler (it is possible to return to ADE explorer again with the inverse procedure).



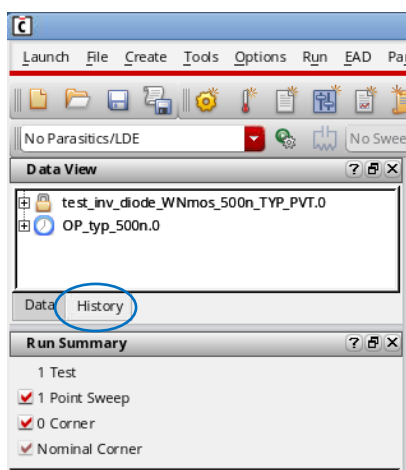
ADE Assembler has the possibility to create multiple “Tests”, with different Analyses, Schematics, configurations, etc.

A very useful feature on ADE Assembler is the possibility to easily access the history of the simulations run. To be able to save different names for each simulation access the “Save Options” dialog box and uncheck the “Overwrite History” option, like the example below.



It is also possible to edit the simulation results location path.

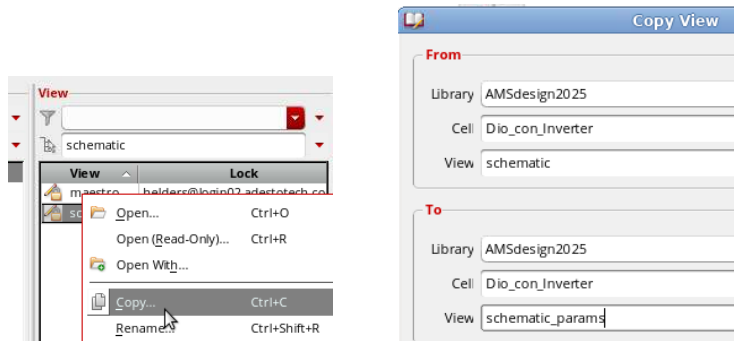
See example below with 3 different simulations on ADE Assembler history dialog box.



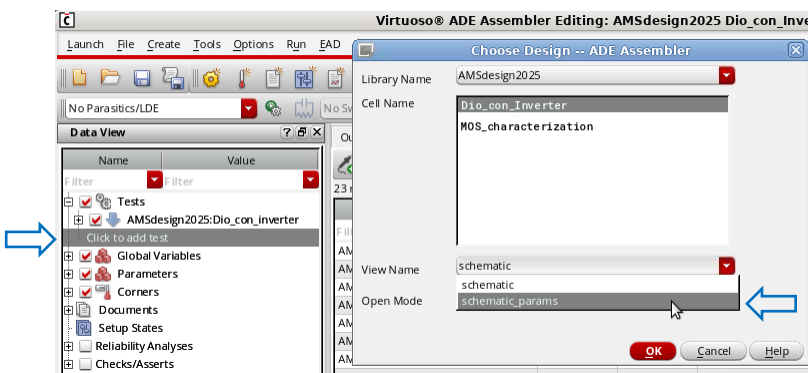
4.5. Add a second test to same Maestro on ADE Assembler

As mentioned above, it is possible to add different tests to the same Maestro Assembler and associate a different schematic.

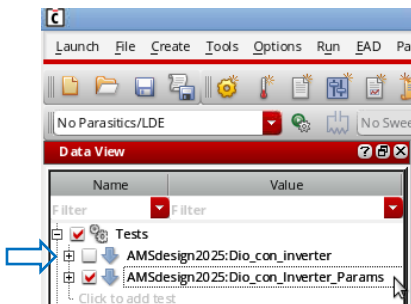
Copy the current schematic view to a new view and give a different name, see example below.



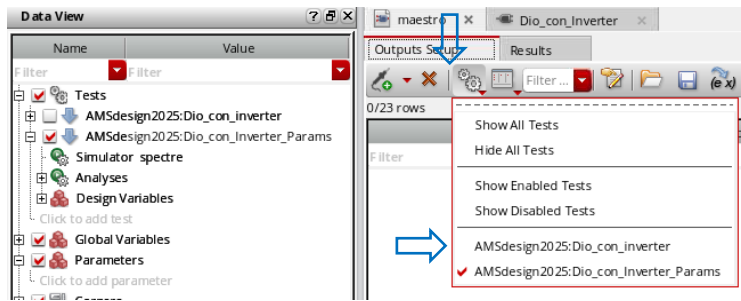
To create a new test setup “Click to add test” and select the current working cell name (“Dio_con_Inverter” on the example above). On the View Name select the new copied version.



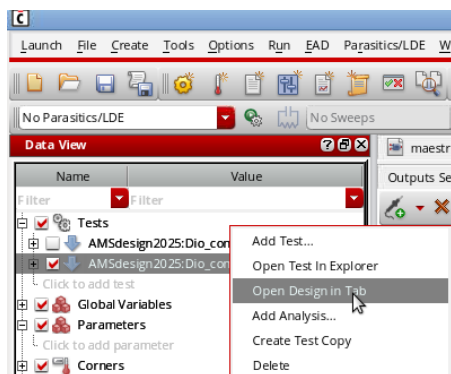
Unselect the first test, so it does not run simultaneously, and give a suitable name to the second test (click twice on the name to edit it). See example below.



To hide the measurements from the first test, uncheck them. See below.

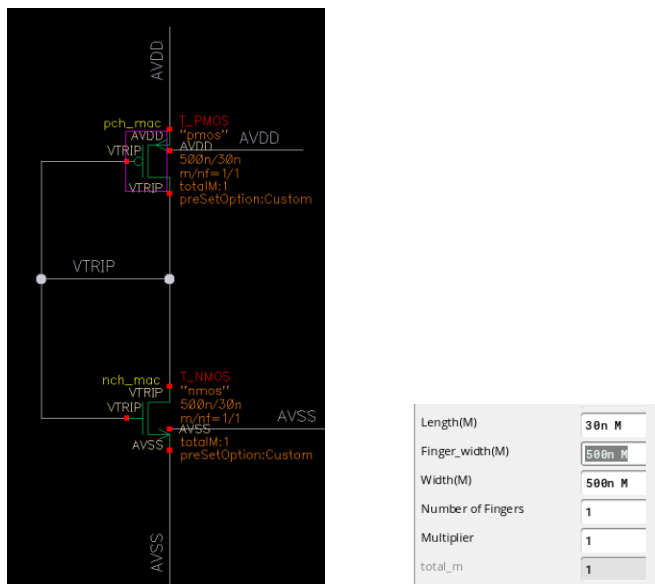


Open the schematic view with design in tab option. See example below.



Confirm the schematic opened is the one you have saved with a different view name ("schematic_params").

On the schematic, delete the variables on both transistors and add fixed values. See example below.



Run the simulation with nominal conditions (typical process and xvdd=0.9V).

Create the following measurements (if necessary, revisit point 3.6 above on how to add expressions to ADE) and edit the specs column as the example below.

Test	Name	Type	Details	EvalType	Plot	Save	Spec	Weight	Units	Digits
Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter
AMSDesign2025:Dio_con_Inverter_Params	Region_NMOS	expr	pv("T_NMOS" ?region" ?result "dcOpInfo")	point	☒	☐	range 1 3	100		
AMSDesign2025:Dio_con_Inverter_Params	Region_PMOS	expr	pv("T_PMOS" ?region" ?result "dcOpInfo")	point	☒	☐	range 1 3	100		
AMSDesign2025:Dio_con_Inverter_Params	V_VTRIP	expr	v("/VTRIP" ?result "dcOp")	point	☒	☐	range 0.445 0.455	80	V	3

We want the transistors to be in saturation (region=2), so define a specification between 1 and 3. The “Weight” column will define the importance of the specification.

Refresh the results tab. As can be seen below not all results are compliant with specifications.

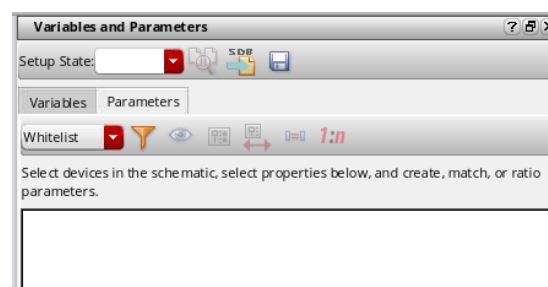
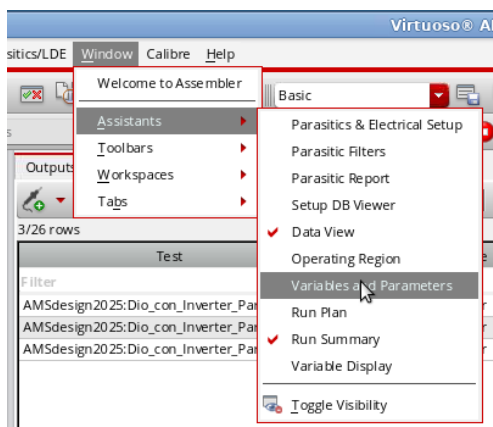
Test	Output	Nominal	Spec	Weight	Pass/Fail
Filter	Filter	Filter	Filter	Filter	Filter
AMSDesign2025:Dio_con_Inverter_Params	Region_NMOS	3	range 1 3	100	near
AMSDesign2025:Dio_con_Inverter_Params	Region_PMOS	2	range 1 3	100	pass
AMSDesign2025:Dio_con_Inverter_Params	V_VTRIP	430 mV	range 0.445 0.455	80	near

Transistors region meaning:
 0 - cut-off
 1 - triode
 2 - saturation
 3 - subthreshold
 4 - breakdown

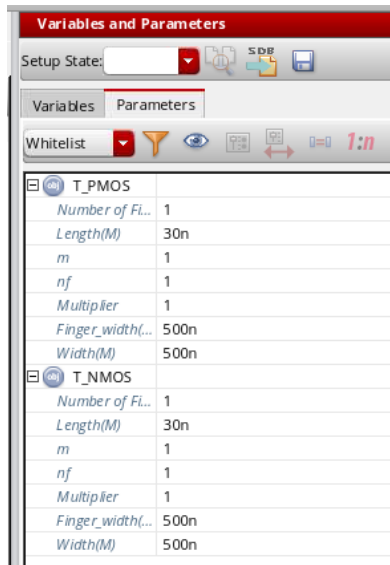
4.6. Configure the optimizer to calculate transistors sizes that comply with all specifications

Instead of running a large number of parametric simulations to find the best size for the transistors to match with the VTRIP specification, it is possible to use the Virtuoso optimizer.

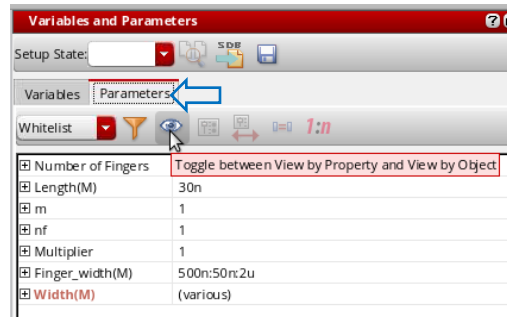
To prepare the Maestro for running the optimizer, it is necessary to set initial values. On ADE assembler open the “Variables and Parameters” tab.



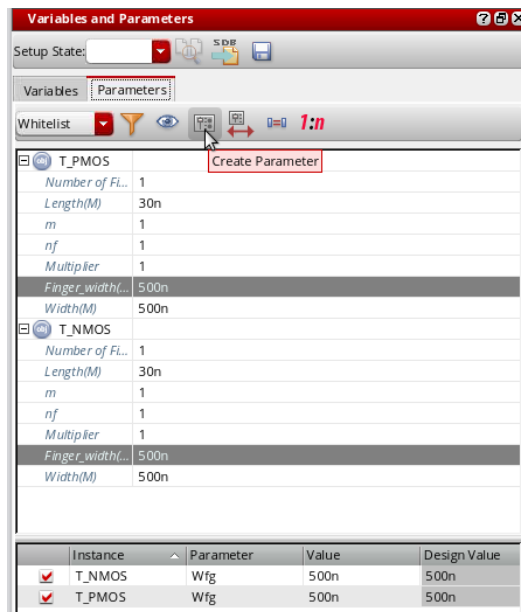
On the schematic editor select the 2 transistors simultaneously and go back to Maestro environment. The transistors parameters should be displayed like the example below.



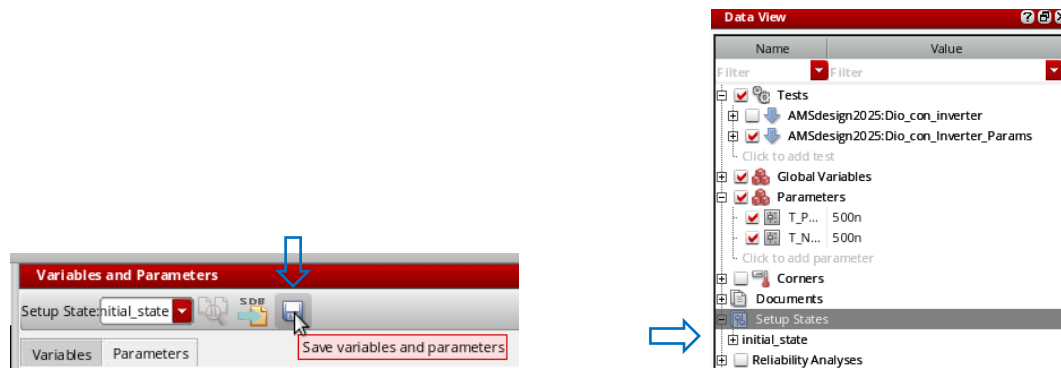
Is possible to toggle between “View by Property” and “View by Object” using the eye tab below.



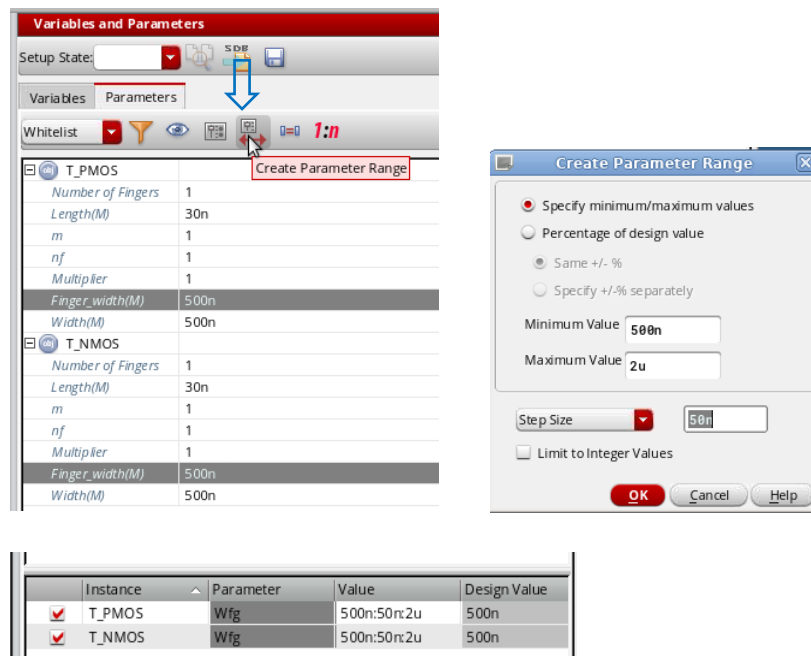
Select both the transistors “Finger_Width(M)” and click on “Create Parameter” icon.



Save the defined parameters as “initial_state” file. Saved state should appear on “Setup States” tab.

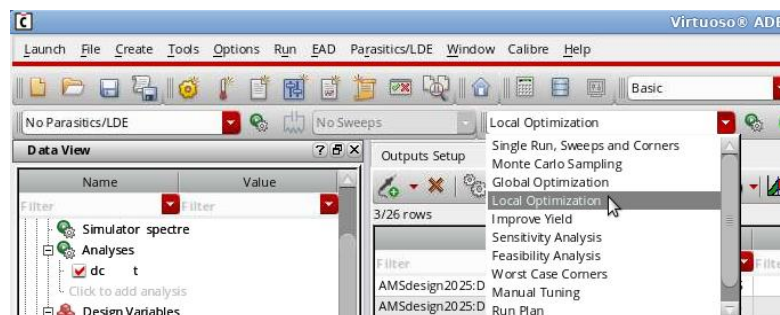


Update the transistors “Finger_Width(M)” value to change from 500nm to 2um in steps of 50nm. See the example below.

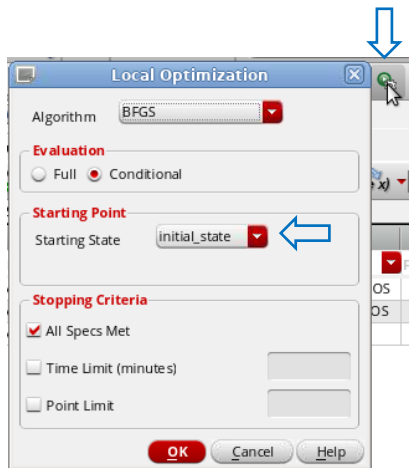


Instance	Parameter	Value	Design Value
☒ T_PMOS	Wfg	500n:50n:2u	500n
☒ T_NMOS	Wfg	500n:50n:2u	500n

Change the type of simulation to “Local Optimization”. See example below.

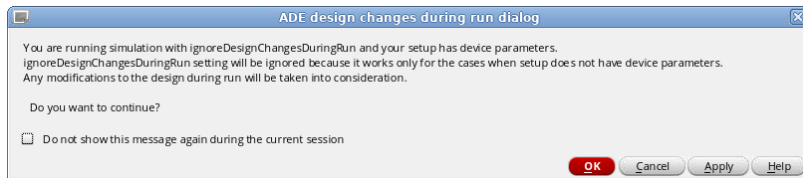


Confirm the “Starting State” on simulation option tab is selected.

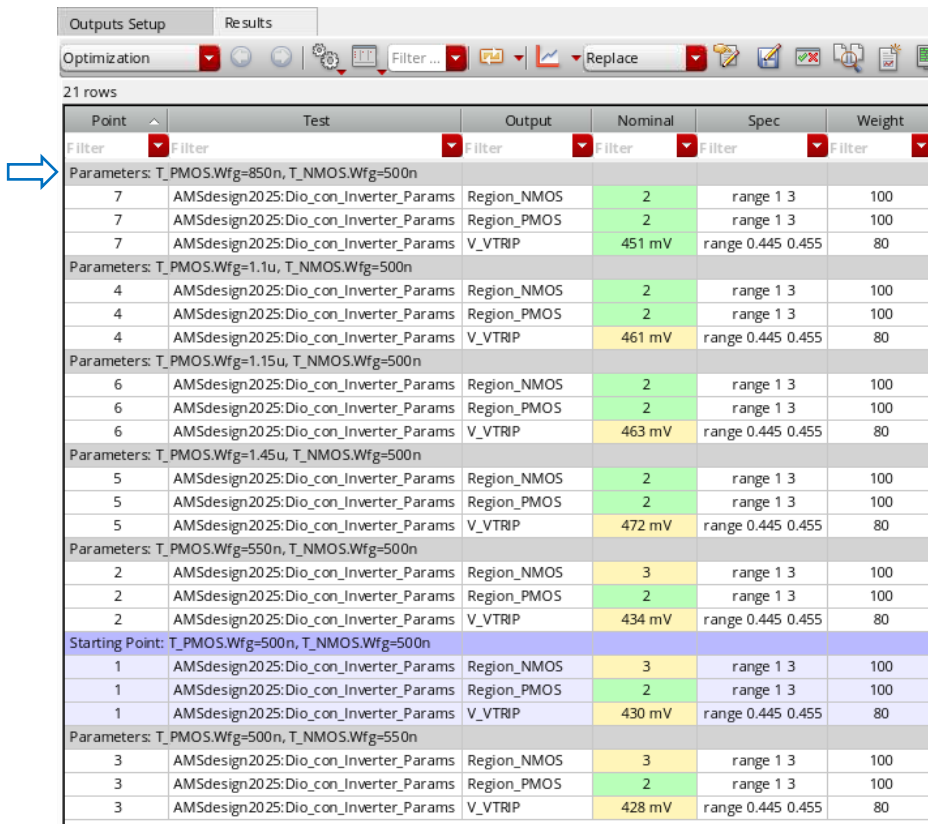


Run the simulation.

If a dialog box like the below appears click Ok, do not change the schematic or Maestro configurations during the optimization simulations process.



The optimization process will start with successive approximations, taking into consideration the specifications and weights given. When all specs are complied, the simulation stops and final sizes are presented.

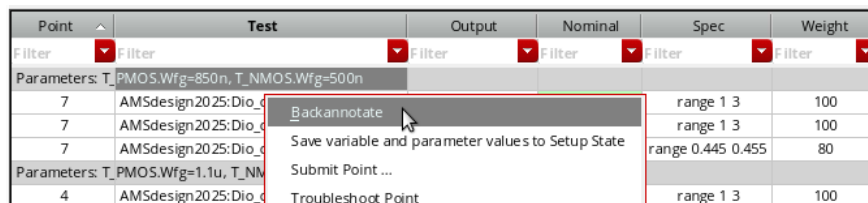


Point	Test	Output	Nominal	Spec	Weight
Filter	Filter	Filter	Filter	Filter	Filter
Parameters: T_PMOS.Wfg=850n, T_NMOS.Wfg=500n					
7	AMSdesign2025:Dio_con_Inverter_Params	Region_NMOS	2	range 1 3	100
7	AMSdesign2025:Dio_con_Inverter_Params	Region_PMOS	2	range 1 3	100
7	AMSdesign2025:Dio_con_Inverter_Params	V_VTRIP	451 mV	range 0.445 0.455	80
Parameters: T_PMOS.Wfg=1.1u, T_NMOS.Wfg=500n					
4	AMSdesign2025:Dio_con_Inverter_Params	Region_NMOS	2	range 1 3	100
4	AMSdesign2025:Dio_con_Inverter_Params	Region_PMOS	2	range 1 3	100
4	AMSdesign2025:Dio_con_Inverter_Params	V_VTRIP	461 mV	range 0.445 0.455	80
Parameters: T_PMOS.Wfg=1.15u, T_NMOS.Wfg=500n					
6	AMSdesign2025:Dio_con_Inverter_Params	Region_NMOS	2	range 1 3	100
6	AMSdesign2025:Dio_con_Inverter_Params	Region_PMOS	2	range 1 3	100
6	AMSdesign2025:Dio_con_Inverter_Params	V_VTRIP	463 mV	range 0.445 0.455	80
Parameters: T_PMOS.Wfg=1.45u, T_NMOS.Wfg=500n					
5	AMSdesign2025:Dio_con_Inverter_Params	Region_NMOS	2	range 1 3	100
5	AMSdesign2025:Dio_con_Inverter_Params	Region_PMOS	2	range 1 3	100
5	AMSdesign2025:Dio_con_Inverter_Params	V_VTRIP	472 mV	range 0.445 0.455	80
Parameters: T_PMOS.Wfg=550n, T_NMOS.Wfg=500n					
2	AMSdesign2025:Dio_con_Inverter_Params	Region_NMOS	3	range 1 3	100
2	AMSdesign2025:Dio_con_Inverter_Params	Region_PMOS	2	range 1 3	100
2	AMSdesign2025:Dio_con_Inverter_Params	V_VTRIP	434 mV	range 0.445 0.455	80
Starting Point: T_PMOS.Wfg=500n, T_NMOS.Wfg=500n					
1	AMSdesign2025:Dio_con_Inverter_Params	Region_NMOS	3	range 1 3	100
1	AMSdesign2025:Dio_con_Inverter_Params	Region_PMOS	2	range 1 3	100
1	AMSdesign2025:Dio_con_Inverter_Params	V_VTRIP	430 mV	range 0.445 0.455	80
Parameters: T_PMOS.Wfg=500n, T_NMOS.Wfg=550n					
3	AMSdesign2025:Dio_con_Inverter_Params	Region_NMOS	3	range 1 3	100
3	AMSdesign2025:Dio_con_Inverter_Params	Region_PMOS	2	range 1 3	100
3	AMSdesign2025:Dio_con_Inverter_Params	V_VTRIP	428 mV	range 0.445 0.455	80

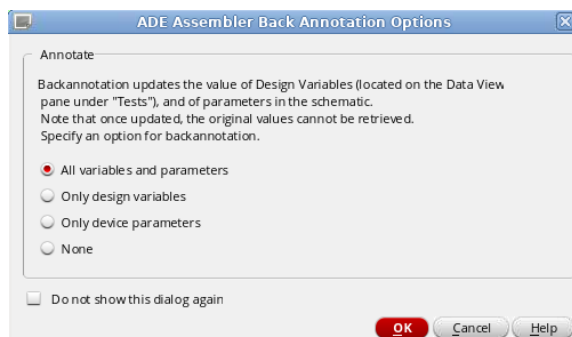
Final results and respective transistors sizes

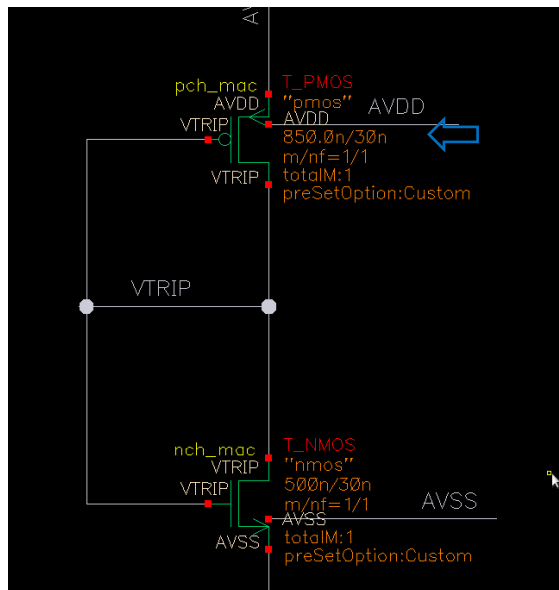
Initial sizes sim results

It is possible to back annotate the parameters to the schematic.



Point	Test	Output	Nominal	Spec	Weight
Filter	Filter	Filter	Filter	Filter	Filter
Parameters: T_PMOS.Wfg=850n, T_NMOS.Wfg=500n					
7	AMSdesign2025:Dio_con_Inverter_Params	Region_NMOS	2	range 1 3	100
7	AMSdesign2025:Dio_con_Inverter_Params	Region_PMOS	2	range 1 3	100
7	AMSdesign2025:Dio_con_Inverter_Params	V_VTRIP	451 mV	range 0.445 0.455	80
Parameters: T_PMOS.Wfg=1.1u, T_NMOS.Wfg=500n					
4	AMSdesign2025:Dio_con_Inverter_Params	Region_NMOS	2	range 1 3	100





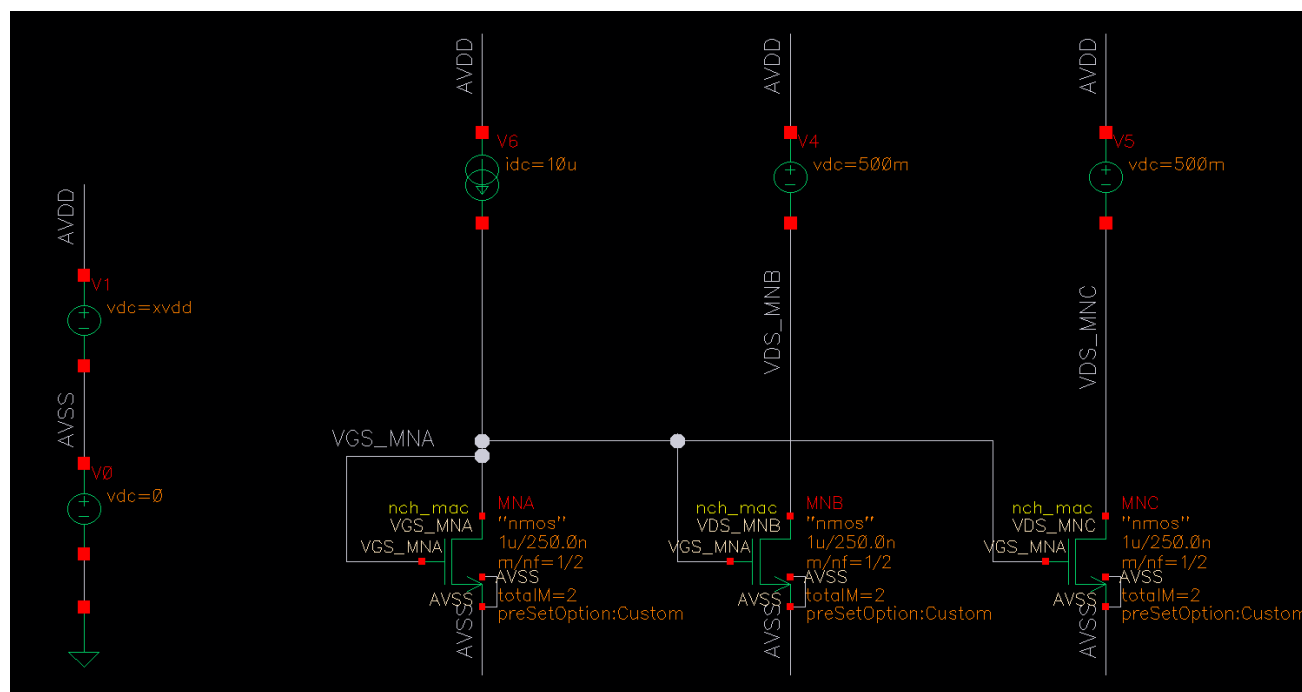
5. PVT corners simulations

5.1. NMOS current mirror schematic

Copy simple NMOS current mirror schematic from reference library.

Library	Cell	View
MODULE_TECH_PVT_MC	NMOS_mirror	schematic

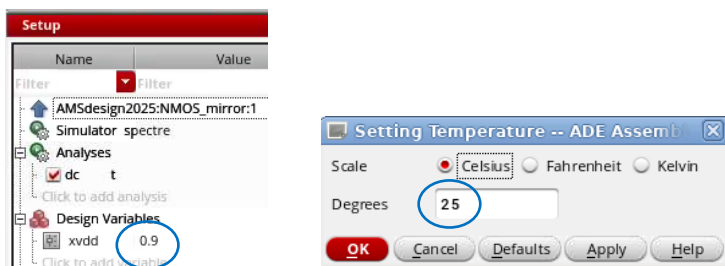
All NMOS have the same size, MNB and MNC have the same VDS voltage. Values have been chosen to set the transistors in saturation region for better current mirroring. An ideal 10uA current is applied to MNA.



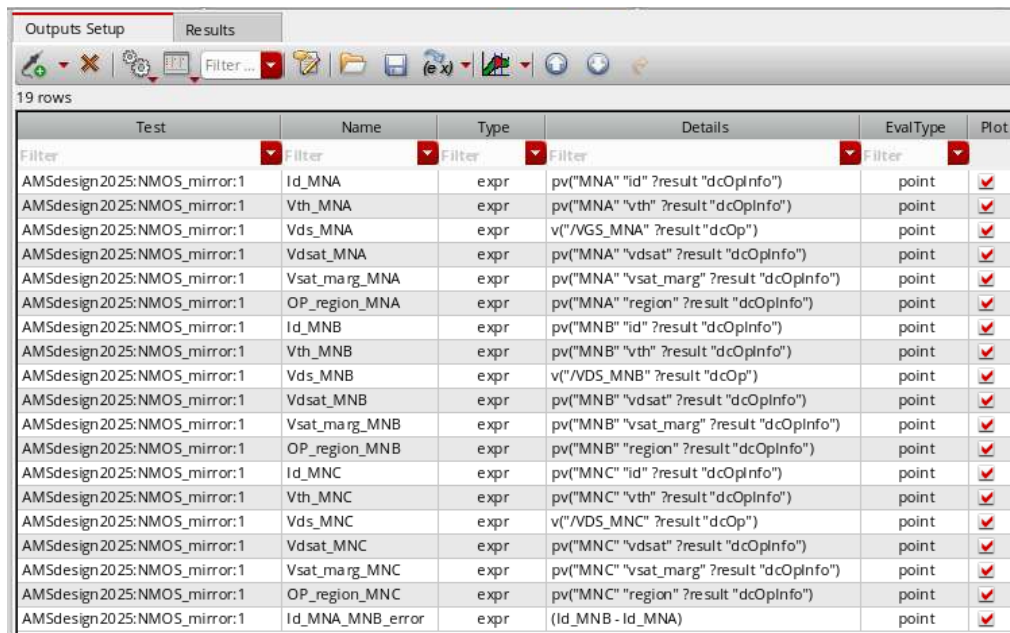
5.2. TYP PVT corner simulation

Create a new Maestro ADE Explorer environment.

Edit Models File path (see point 3.5 for more details). Configure the devices models section as “TTTT_RT_CT_BT” (typical Process), supply voltage as 0.9V (typical technology supply value) and temperature as typical 25°C.



Run the simulation with the above operating conditions and save the following measures to ADE (follow the same steps presented on point 3.6 above).



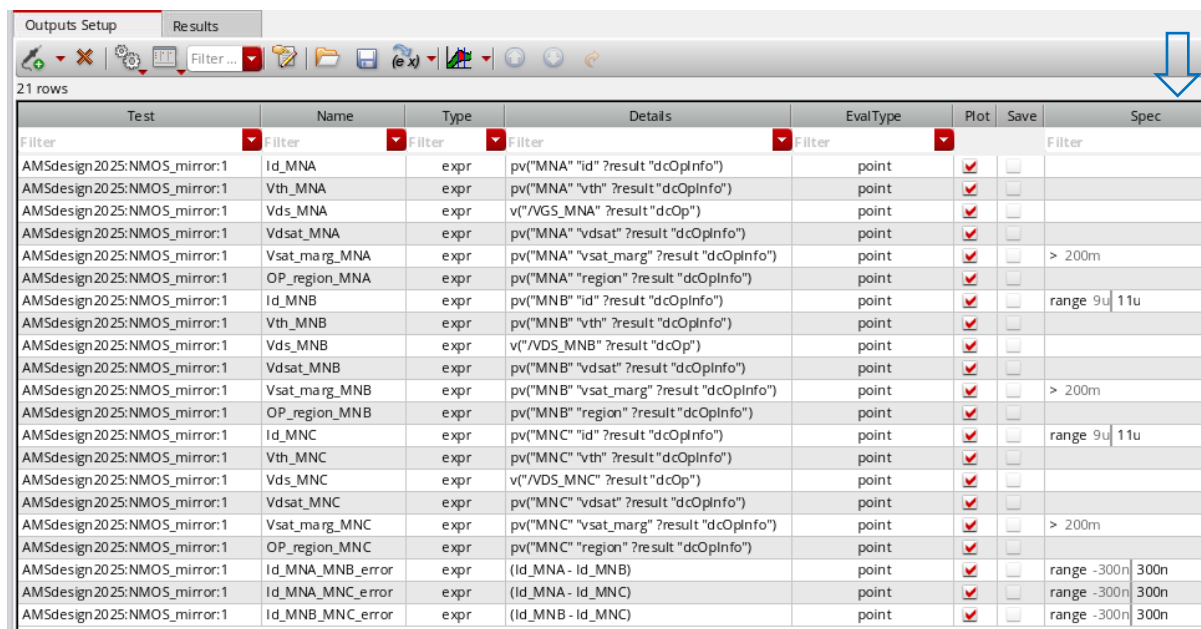
Test	Name	Type	Details	EvalType	Plot
Filter	Filter	Filter	Filter	Filter	Filter
AMSdesign2025:NMOS_mirror:1	Id_MNA	expr	pv("MNA" "id" ?result "dcOpInfo")	point	✓
AMSdesign2025:NMOS_mirror:1	Vth_MNA	expr	pv("MNA" "vth" ?result "dcOpInfo")	point	✓
AMSdesign2025:NMOS_mirror:1	Vds_MNA	expr	v("/VGS_MNA" ?result "dcOp")	point	✓
AMSdesign2025:NMOS_mirror:1	Vdsat_MNA	expr	pv("MNA" "vdsat" ?result "dcOpInfo")	point	✓
AMSdesign2025:NMOS_mirror:1	Vsat_marg_MNA	expr	pv("MNA" "vsat_marg" ?result "dcOpInfo")	point	✓
AMSdesign2025:NMOS_mirror:1	OP_region_MNA	expr	pv("MNA" "region" ?result "dcOpInfo")	point	✓
AMSdesign2025:NMOS_mirror:1	Id_MNB	expr	pv("MNB" "id" ?result "dcOpInfo")	point	✓
AMSdesign2025:NMOS_mirror:1	Vth_MNB	expr	pv("MNB" "vth" ?result "dcOpInfo")	point	✓
AMSdesign2025:NMOS_mirror:1	Vds_MNB	expr	v("/VDS_MNB" ?result "dcOp")	point	✓
AMSdesign2025:NMOS_mirror:1	Vdsat_MNB	expr	pv("MNB" "vdsat" ?result "dcOpInfo")	point	✓
AMSdesign2025:NMOS_mirror:1	Vsat_marg_MNB	expr	pv("MNB" "vsat_marg" ?result "dcOpInfo")	point	✓
AMSdesign2025:NMOS_mirror:1	OP_region_MNB	expr	pv("MNB" "region" ?result "dcOpInfo")	point	✓
AMSdesign2025:NMOS_mirror:1	Id_MNC	expr	pv("MNC" "id" ?result "dcOpInfo")	point	✓
AMSdesign2025:NMOS_mirror:1	Vth_MNC	expr	pv("MNC" "vth" ?result "dcOpInfo")	point	✓
AMSdesign2025:NMOS_mirror:1	Vds_MNC	expr	v("/VDS_MNC" ?result "dcOp")	point	✓
AMSdesign2025:NMOS_mirror:1	Vdsat_MNC	expr	pv("MNC" "vdsat" ?result "dcOpInfo")	point	✓
AMSdesign2025:NMOS_mirror:1	Vsat_marg_MNC	expr	pv("MNC" "vsat_marg" ?result "dcOpInfo")	point	✓
AMSdesign2025:NMOS_mirror:1	OP_region_MNC	expr	pv("MNC" "region" ?result "dcOpInfo")	point	✓
AMSdesign2025:NMOS_mirror:1	Id_MNA_MNB_error	expr	(Id_MNB - Id_MNA)	point	✓

Alternatively, load the following pre-defined measurements file path:

~\IC6_workspace / MODULE_TECH_PVT_MC / outputs_AMSdesign2025_NMOS_mirror_maestro.csv

5.3. Define Specifications values (specs) for the measures

One good way to easily evaluate if a measurement is close or even out of specification is to add min/max or range values into ADE and the result will be plotted with a color scheme. See examples below:



Test	Name	Type	Details	EvalType	Plot	Save	Spec
Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter
AMSdesign2025:NMOS_mirror:1	Id_MNA	expr	pv("MNA" "id" ?result "dcOpInfo")	point	✓		
AMSdesign2025:NMOS_mirror:1	Vth_MNA	expr	pv("MNA" "vth" ?result "dcOpInfo")	point	✓		
AMSdesign2025:NMOS_mirror:1	Vds_MNA	expr	v("/VGS_MNA" ?result "dcOp")	point	✓		
AMSdesign2025:NMOS_mirror:1	Vdsat_MNA	expr	pv("MNA" "vdsat" ?result "dcOpInfo")	point	✓		
AMSdesign2025:NMOS_mirror:1	Vsat_marg_MNA	expr	pv("MNA" "vsat_marg" ?result "dcOpInfo")	point	✓		> 200m
AMSdesign2025:NMOS_mirror:1	OP_region_MNA	expr	pv("MNA" "region" ?result "dcOpInfo")	point	✓		
AMSdesign2025:NMOS_mirror:1	Id_MNB	expr	pv("MNB" "id" ?result "dcOpInfo")	point	✓		range 9u 11u
AMSdesign2025:NMOS_mirror:1	Vth_MNB	expr	pv("MNB" "vth" ?result "dcOpInfo")	point	✓		
AMSdesign2025:NMOS_mirror:1	Vds_MNB	expr	v("/VDS_MNB" ?result "dcOp")	point	✓		
AMSdesign2025:NMOS_mirror:1	Vdsat_MNB	expr	pv("MNB" "vdsat" ?result "dcOpInfo")	point	✓		
AMSdesign2025:NMOS_mirror:1	Vsat_marg_MNB	expr	pv("MNB" "vsat_marg" ?result "dcOpInfo")	point	✓		> 200m
AMSdesign2025:NMOS_mirror:1	OP_region_MNB	expr	pv("MNB" "region" ?result "dcOpInfo")	point	✓		
AMSdesign2025:NMOS_mirror:1	Id_MNC	expr	pv("MNC" "id" ?result "dcOpInfo")	point	✓		range 9u 11u
AMSdesign2025:NMOS_mirror:1	Vth_MNC	expr	pv("MNC" "vth" ?result "dcOpInfo")	point	✓		
AMSdesign2025:NMOS_mirror:1	Vds_MNC	expr	v("/VDS_MNC" ?result "dcOp")	point	✓		
AMSdesign2025:NMOS_mirror:1	Vdsat_MNC	expr	pv("MNC" "vdsat" ?result "dcOpInfo")	point	✓		
AMSdesign2025:NMOS_mirror:1	Vsat_marg_MNC	expr	pv("MNC" "vsat_marg" ?result "dcOpInfo")	point	✓		> 200m
AMSdesign2025:NMOS_mirror:1	OP_region_MNC	expr	pv("MNC" "region" ?result "dcOpInfo")	point	✓		
AMSdesign2025:NMOS_mirror:1	Id_MNA_MNB_error	expr	(Id_MNB - Id_MNA)	point	✓		range -300n 300n
AMSdesign2025:NMOS_mirror:1	Id_MNA_MNC_error	expr	(Id_MNA - Id_MNC)	point	✓		range -300n 300n
AMSdesign2025:NMOS_mirror:1	Id_MNB_MNC_error	expr	(Id_MNB - Id_MNC)	point	✓		range -300n 300n

5.4. Typical corner simulation results

Run the simulation configured with typical operating conditions (TYP PVT). See below an example of results.

Test	Output	Nominal	Spec	Weight	Pass/Fail
AMSDesign2025:NMO5_mirror:1	Id_MNA	10u			
AMSDesign2025:NMO5_mirror:1	Vth_MNA	463m			
AMSDesign2025:NMO5_mirror:1	Vds_MNA	499.6m			
AMSDesign2025:NMO5_mirror:1	Vdsat_MNA	115.6m			
AMSDesign2025:NMO5_mirror:1	Vsat_marg_MNA	384m	> 200m		pass
AMSDesign2025:NMO5_mirror:1	OP_region_MNA	2			
AMSDesign2025:NMO5_mirror:1	Id_MNB	9.883u	range 9u 11u		pass
AMSDesign2025:NMO5_mirror:1	Vth_MNB	463m			
AMSDesign2025:NMO5_mirror:1	Vds_MNB	400m			
AMSDesign2025:NMO5_mirror:1	Vdsat_MNB	115.6m			
AMSDesign2025:NMO5_mirror:1	Vsat_marg_MNB	284.4m	> 200m		pass
AMSDesign2025:NMO5_mirror:1	OP_region_MNB	2			
AMSDesign2025:NMO5_mirror:1	Id_MNC	9.883u	range 9u 11u		pass
AMSDesign2025:NMO5_mirror:1	Vth_MNC	463m			
AMSDesign2025:NMO5_mirror:1	Vds_MNC	400m			
AMSDesign2025:NMO5_mirror:1	Vdsat_MNC	115.6m			
AMSDesign2025:NMO5_mirror:1	Vsat_marg_MNC	284.4m	> 200m		pass
AMSDesign2025:NMO5_mirror:1	OP_region_MNC	2			
AMSDesign2025:NMO5_mirror:1	Id_MNA_MNB_error	117.3n	range -300n 300n		pass
AMSDesign2025:NMO5_mirror:1	Id_MNA_MNC_error	117.3n	range -300n 300n		pass
AMSDesign2025:NMO5_mirror:1	Id_MNB_MNC_error	0	range -300n 300n		pass

Transistors MNB and MNC have the same operating conditions, as expected, they have equal drain currents. Although, they are different from MNA due to different Vds voltages.

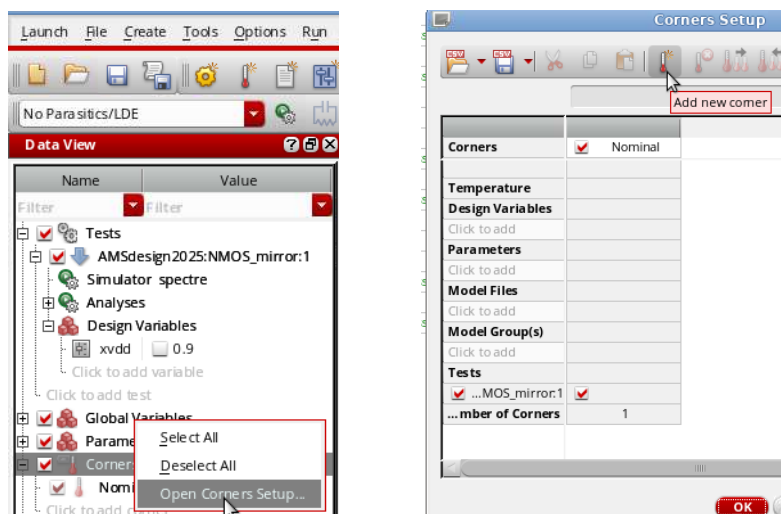
All transistors are on saturation region with good saturation margins.

Transistors region meaning:

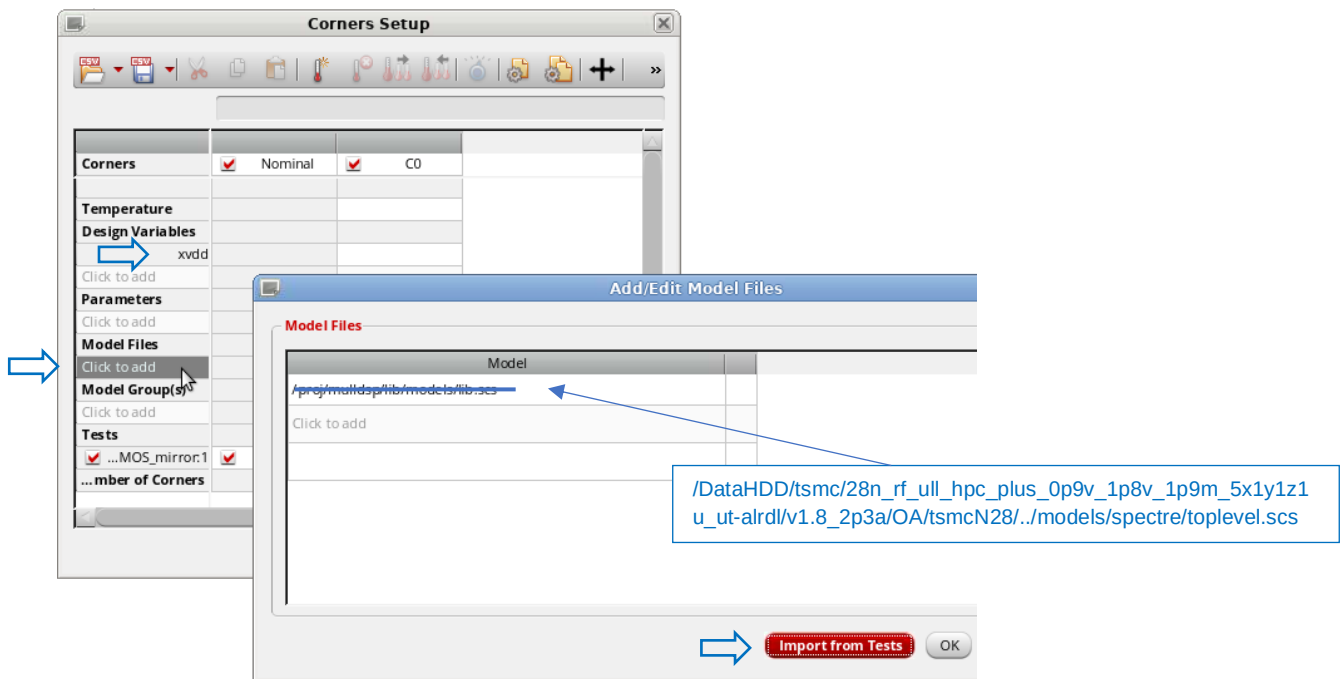
- 0 - cut-off
- 1 - triode
- 2 - saturation
- 3 - subthreshold
- 4 - breakdown

5.5. Define corner variations

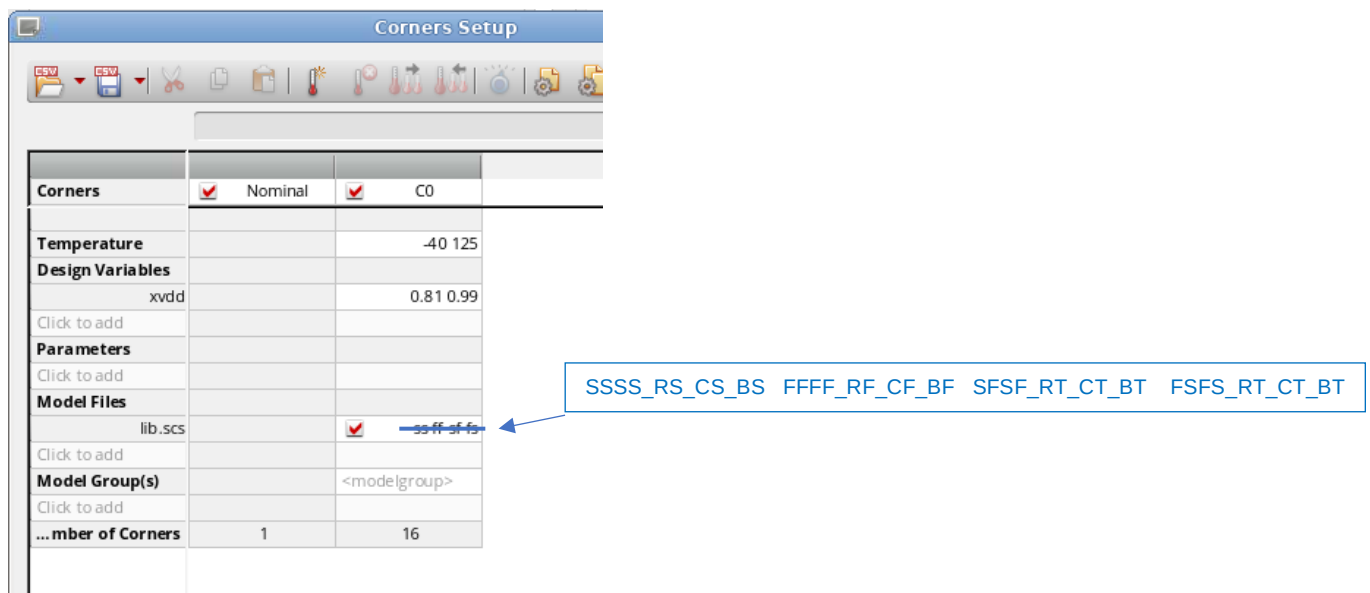
To add PVT corner variations, launch the “Open Corners Setup...” dialog box and add a new corner.



On the new corner add the “Design Variables” and “Model Files” paths, as the example below:



Add the Process, Voltage and Temperature corner values to be simulated.



Please note, the ADE will cross all values added independently and run a simulation for each possible combination. The total number of simulations is added to the bottom of corners setup dialog box.

5.6. Corners simulations results

Run the PVT corners simulations. See example of results below:

Outputs Setup		Results																					
Detail																							
Parameter		Nominal						CO_0	CO_1	CO_2	CO_3	CO_4	CO_5	CO_6	CO_7	CO_8	CO_9	CO_10	CO_11	CO_12	CO_13	CO_14	CO_15
lib.scs	tt	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss
temperature	25	-40	125	-40	125	-40	125	-40	125	-40	125	-40	125	-40	125	-40	125	-40	125	-40	125	-40	125
axdvd	900m	810m	810m	990m	990m	810m	810m	990m	990m	810m	810m	990m	990m	810m	810m	990m	990m	810m	810m	990m	990m	810m	810m
21 rows																							
Test	Output	Nominal	Spec	Weight	Pass/Fail	Min	Max	CO_0	CO_1	CO_2	CO_3	CO_4	CO_5	CO_6	CO_7	CO_8	CO_9	CO_10	CO_11	CO_12	CO_13	CO_14	CO_15
Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter
AM5design2025.NMOS_miror:1	Id_MNA	10u				10u	10.01u	10u	10u	10u	10u	10u	10u	10u	10.01u	10u	10.01u	10u	10u	10u	10.01u	10.01u	10u
AM5design2025.NMOS_miror:1	Vth_MNA	463m				387.8m	520.7m	520.7m	444.9m	520.7m	444.9m	463.6m	387.8m	463.6m	387.8m	515.3m	439.5m	515.3m	439.5m	470.2m	394.4m	470.2m	394.4m
AM5design2025.NMOS_miror:1	Vds_MNA	499.6m				418.8m	561.9m	561.9m	478.3m	561.9m	478.4m	502.3m	418.8m	502.3m	418.9m	554.6m	470.9m	554.6m	470.8m	509.4m	425.9m	509.5m	425.9m
AM5design2025.NMOS_miror:1	Vdsat_MNA	115.6m				96.5m	143.1m	97.86m	142.1m	97.86m	142.1m	96.5m	139.8m	96.51m	139.8m	98.45m	143.1m	98.46m	143m	96.88m	140.4m	96.93m	140.4m
AM5design2025.NMOS_miror:1	Vsat_mag_MNA	384m	> 200m		pass	279m	464m	464m	336.2m	464m	336.2m	405.8m	279m	405.8m	279m	456.2m	327.8m	456.2m	327.7m	412.5m	285.5m	412.6m	285.5m
AM5design2025.NMOS_miror:1	OP_region_MNA	2				2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2
AM5design2025.NMOS_miror:1	Id_MNB	9.883u	range 9u 11u		pass	9.696u	10.09u	9.696u	9.781u	9.931u	10.01u	9.731u	9.837u	9.99u	10.09u	9.697u	9.795u	9.936u	10.02u	9.726u	9.834u	9.992u	10.08u
AM5design2025.NMOS_miror:1	Vth_MNB	463m				387.8m	520.7m	520.7m	444.9m	520.7m	444.9m	463.6m	387.8m	463.6m	387.8m	515.3m	439.5m	515.3m	439.5m	470.2m	394.4m	470.2m	394.4m
AM5design2025.NMOS_miror:1	Vds_MNB	490m				310m	490m	310m	310m	490m	490m	310m	310m	490m	490m	310m	490m	490m	490m	310m	310m	490m	490m
AM5design2025.NMOS_miror:1	Vdsat_MNB	115.6m				96.5m	143.1m	97.86m	142.1m	97.86m	142.1m	96.5m	139.8m	96.51m	139.8m	98.45m	143.1m	98.46m	143m	96.88m	140.4m	96.93m	140.4m
AM5design2025.NMOS_miror:1	Vsat_mag_MNB	284.4m	> 200m		fail	166.9m	393.5m	212.1m	167.9m	392.1m	347.9m	213.5m	170.2m	393.5m	350.2m	211.5m	166.9m	391.5m	347m	213.1m	169.6m	393.1m	349.6m
AM5design2025.NMOS_miror:1	OP_region_MNB	2				2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2
AM5design2025.NMOS_miror:1	Id_MNC	9.883u	range 9u 11u		pass	9.696u	10.09u	9.696u	9.781u	9.931u	10.01u	9.731u	9.837u	9.99u	10.09u	9.697u	9.795u	9.936u	10.02u	9.726u	9.834u	9.992u	10.08u
AM5design2025.NMOS_miror:1	Vth_MNC	463m				387.8m	520.7m	520.7m	444.9m	520.7m	444.9m	463.6m	387.8m	463.6m	387.8m	515.3m	439.5m	515.3m	439.5m	470.2m	394.4m	470.2m	394.4m
AM5design2025.NMOS_miror:1	Vds_MNC	490m				310m	490m	310m	310m	490m	490m	310m	310m	490m	490m	310m	490m	490m	490m	310m	310m	490m	490m
AM5design2025.NMOS_miror:1	Vdsat_MNC	115.6m				96.5m	143.1m	97.86m	142.1m	97.86m	142.1m	96.5m	139.8m	96.51m	139.8m	98.45m	143.1m	98.46m	143m	96.88m	140.4m	96.93m	140.4m
AM5design2025.NMOS_miror:1	Vsat_mag_MNC	284.4m	> 200m		fail	166.9m	393.5m	212.1m	167.9m	392.1m	347.9m	213.5m	170.2m	393.5m	350.2m	211.5m	166.9m	391.5m	347m	213.1m	169.6m	393.1m	349.6m
AM5design2025.NMOS_miror:1	OP_region_MNC	2				2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2
AM5design2025.NMOS_miror:1	Id_MNA_MNB_error	117.3m	range -300n 300n		near	-84.43n	304.3n	304.3n	218.7n	70.16n	-11.8n	270.9n	165.2n	140.7n	-84.43n	303.2n	214.6n	64.73n	-19.99n	275.5n	172.9n	21.8n	-74.69n
AM5design2025.NMOS_miror:1	Id_MNA_MNC_error	117.3m	range -300n 300n		near	-84.43n	304.3n	304.3n	218.7n	70.16n	-11.8n	270.9n	165.2n	140.7n	-84.43n	303.2n	214.6n	64.73n	-19.99n	275.5n	172.9n	21.8n	-74.69n
AM5design2025.NMOS_miror:1	Id_MNB_MNC_error	0	range -300n 300n		pass	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0

As can be seen from the simulations results, some of the measurements do not pass all the specifications on all corner conditions. At this point you can edit the transistors' sizes to improve the circuits' performance and try to comply with all the specifications. Or, if specifications are extremely hard to comply with, new architectures can be tested.

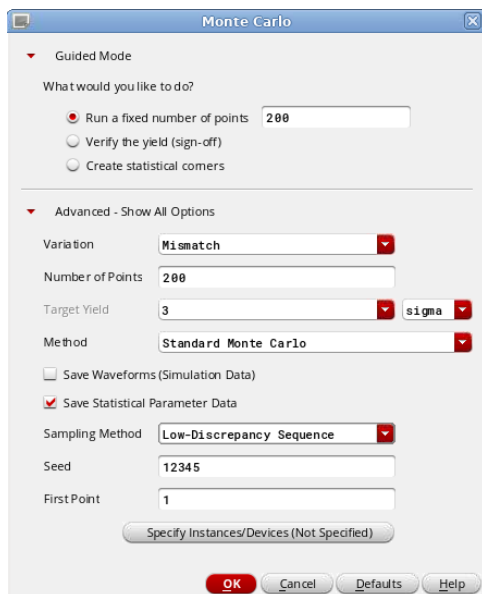
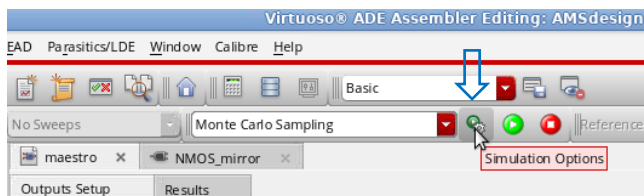
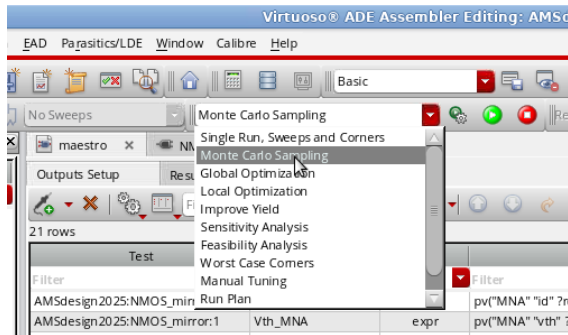
For example, increase the number of fingers (nf) of all transistors from 2 to 6 and increase the length (L) of all transistors from 250nm to 500nm. See example below of simulation results for increased transistors sizes.

Outputs Setup		Results																					
Detail																							
	Parameter	Nominal						CO_0	CO_1	CO_2	CO_3	CO_4	CO_5	CO_6	CO_7	CO_8	CO_9	CO_10	CO_11	CO_12	CO_13	CO_14	CO_15
	lib.scs	globalmc_jo...	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss	ss
	temperature	25						-40	125	-40	125	-40	125	-40	125	-40	125	-40	125	-40	125	-40	125
	axdvd	900m						810m	810m	990m	990m	810m	810m	990m	990m	810m	810m	990m	990m	810m	810m	990m	990m
21 rows																							
Test	Output	Nominal	Spec	Weight	Pass/Fail	Min	Max	CO_0	CO_1	CO_2	CO_3	CO_4	CO_5	CO_6	CO_7	CO_8	CO_9	CO_10	CO_11	CO_12	CO_13	CO_14	CO_15
Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter	Filter
AM5design2025.NMOS_miror:1	Id_MNA	10.01u				10u	10.01u	10u	10u	10u	10u	10u	10.01u	10u	10u	10u	10u	10u	10u	10u	10.01u	10u	10u
AM5design2025.NMOS_miror:1	Vth_MNA	467.1m				390.7m	525.1m	525.1m	445.9m	525.1m	445.9m	470m	390.7m	470m	390.7m	519.7m	440.5m	519.7m	440.5m	476.6m	397.4m	476.6m	397.4m
AM5design2025.NMOS_miror:1	Vds_MNA	483m				399.2m	547m	547m	456.1m	547m	456.1m	490.1m	399.2m	490.1m	399.2m	540.1m	449m	540.1m	449m	497m	406.1m	497m	406.1m
AM5design2025.NMOS_miror:1	Vdsat_MNA	96.73m				78.79m	117.6m	79.04m	116.6m	79.04m	116.6m	78.8m	116m	78.79m	116m	79.7m	117.6m	79.69m	117.6m	78.97m	116.2m	78.93m	116.2m
AM5design2025.NMOS_miror:1	Vsat_mag_MNA	388.3m	> 200m		pass	283.2m	467.9m	467.9m	339.4m	467.9m	339.4m	411.3m	283.2m	411.3m	283.2m	460.4m	331.4m	460.4m	331.4m	418.1m	289.9m	418m	289.9m
AM5design2025.NMOS_miror:1	OP_region_MNA	2				2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2
AM5design2025.NMOS_miror:1	Id_MNB	9.949u	range 9u 11u		pass	9.834u	10.06u	9.834u	9.892u	9.967u	10.02u	9.848u	9.93u	10u	10.06u	9.835u	9.893u	9.97u	10.02u	9.857u	9.919u	9.996u	10.06u
AM5design2025.NMOS_miror:1	Vth_MNB	467.1m				390.7m	525.1m	525.1m	445.9m	525.1m	445.9m	470m	390.7m	470m	390.7m	519.7m	440.5m	519.7m	440.5m	476.6m	397.4m	476.6m	397.4m
AM5design2025.NMOS_miror:1	Vds_MNB	490m				310m	490m	310m	310m	490m	490m	310m	310m	490m	490m	310m	490m	490m	490m	310m	310m	490m	490m
AM5design2025.NMOS_miror:1	Vdsat_MNB	96.73m				78.79m	117.6m	79.04m	116.6m	79.04m	116.6m	78.8m	116m	78.79m	116m	79.7m	117.6m	79.69m	117.6m	78.97m	116.2m	78.93m	116.2m
AM5design2025.NMOS_miror:1	Vsat_mag_MNB	305.2m	> 200m		near	192.4m	411.2m	231m	193.4m	411m	373.4m	231.2m	194m	411.2m	374m	230.3m	192.4m	410.3m	372.4m	231m	193.8m	411.1m	373.8m
AM5design2025.NMOS_miror:1	OP_region_MNB	2				2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2
AM5design2025.NMOS_miror:1	Id_MNC	9.949u	range 9u 11u		pass	9.834u	10.06u	9.834u	9.892u	9.967u	10.02u	9.848u	9.93u	10u	10.06u	9.835u	9.893u	9.97u	10.02u	9.857u	9.919u	9.996u	10.06u
AM5design2025.NMOS_miror:1	Vth_MNC	467.1m				390.7m	525.1m	525.1m	445.9m	525.1m	445.9m	470m	390.7m	470m	390.7m	519.7m	440.5m	519.7m	440.5m	476.6m	397.4m	476.6m	397.4m
AM5design2025.NMOS_miror:1	Vds_MNC	490m				310m	490m	310m	310m	490m	490m	310m	310m	490m	490m	310m	490m	490m	490m	310m	310m	490m	490m
AM5design2025.NMOS_miror:1	Vdsat_MNC	96.73m				78.79m	117.6m	79.04m	116.6m	79.04m	116.6m	78.8m	116m	78.79m	116m	79.7m	117.6m	79.69m	117.6m	78.97m	116.2m	78.93m	116.2m
AM5design2025.NMOS_miror:1	Vsat_mag_MNC	305.2m	> 200m		near	192.4m	411.2m	231m	193.4m	411m	373.4m	231.2m	194m	411.2m	374m	230.3m	192.4m	410.3m	372.4m	231m	193.8m	411.1m	373.8m
AM5design2025.NMOS_miror:1	OP_region_MNC	2				2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2	2
AM5design2025.NMOS_miror:1	Id_MNA_MNC_error	56.98n	range -300n 300n		pass	-63n	168.4n	168.4n	109.3n	33.27n	-19.33n	153.8n	85.77n	39.37n	-63n	168.2n	107.1n	30.11n	-24.07n	156.9n	85.77n	4.812n	-57.03n
AM5design2025.NMOS_miror:1	Id_MNA_MNC_error	56.98n	range -300n 300n		pass	-63n	168.4n	168.4n	109.3n	33.27n	-19.33n	153.8n	81.17n	39.37n	-63n	168.2n	107.1n	30.11n	-24.07n	156.9n	85.77n	4.812n	-57.03n
AM5design2025.NMOS_miror:1	Id_MNB_MNC_error	0	range -300n 300n		pass	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0

6. Monte-Carlo simulations

6.1. Configuration of Monte-Carlo simulations

To run simulations of devices process and mismatch variations select the “Monte Carlo Sampling” option on same NMOS current mirror testbench simulated on previous point and open the respective simulations configuration tool.



The number of points will be equivalent to the number of simulations, each one with different variations of each device parameters.

3 types of variations are available:

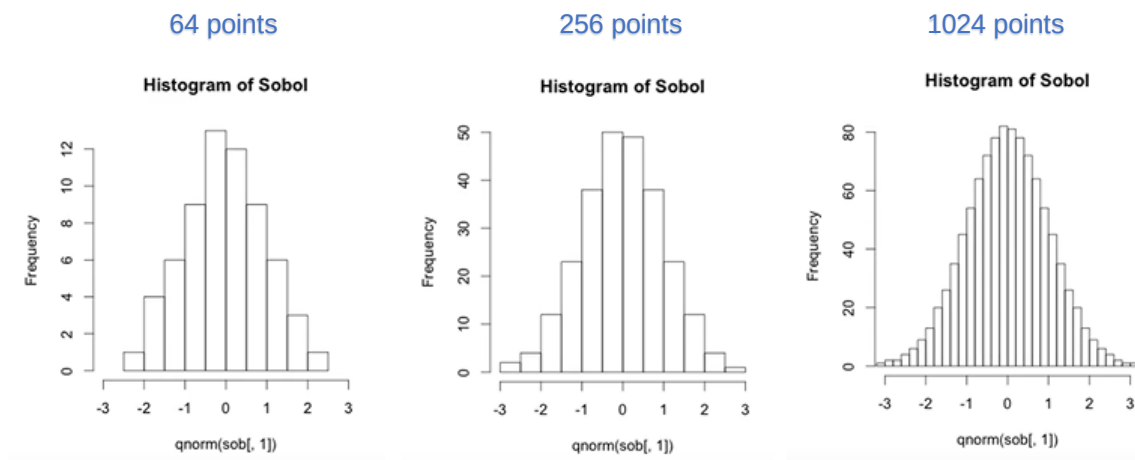
- All (Process + Mismatch)
- Mismatch
- Process

3 Sampling Method are available:

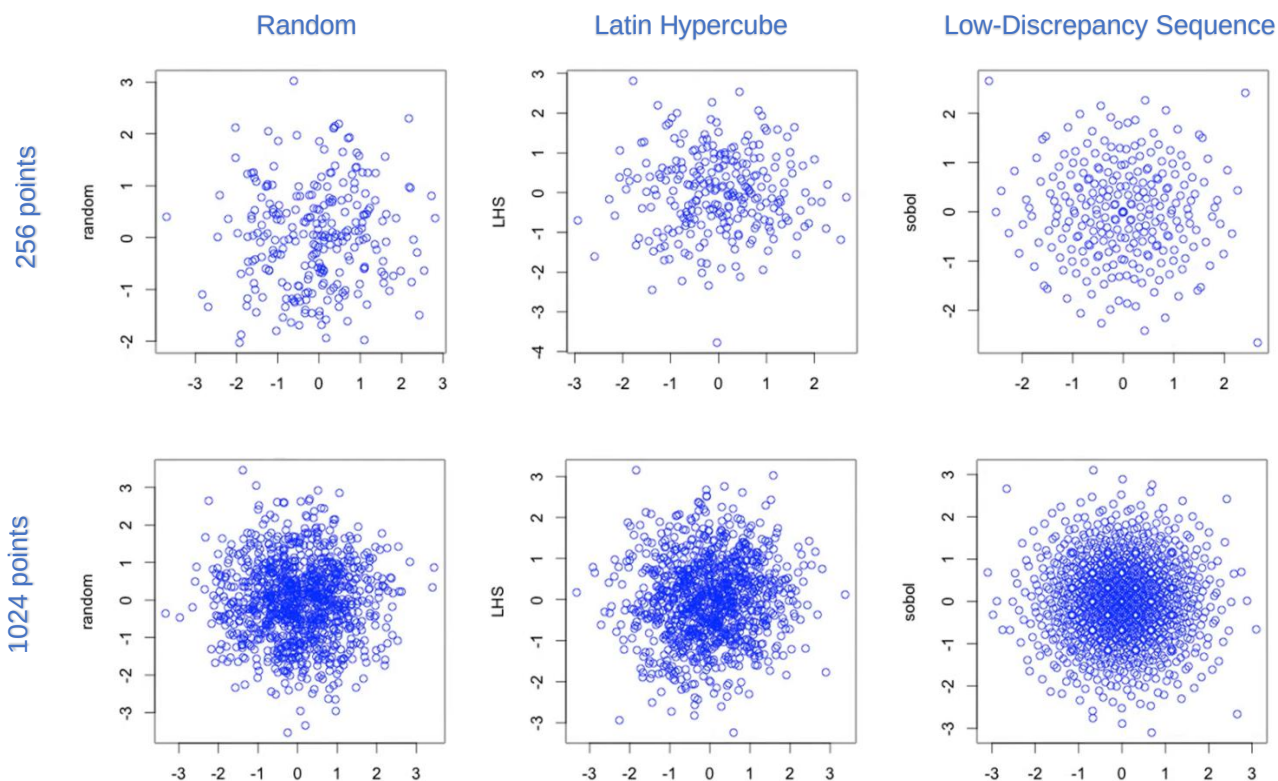
- Random
- Latin Hypercube
- Low-Discrepancy Sequence

Select the “Mismatch” variation, “Low-Discrepancy Sequence” sampling method and 200 points.

The higher the number of points the more accurate the statistical analysis will be. See example below of Gaussian distribution for different number of points (source Cadence Community website):

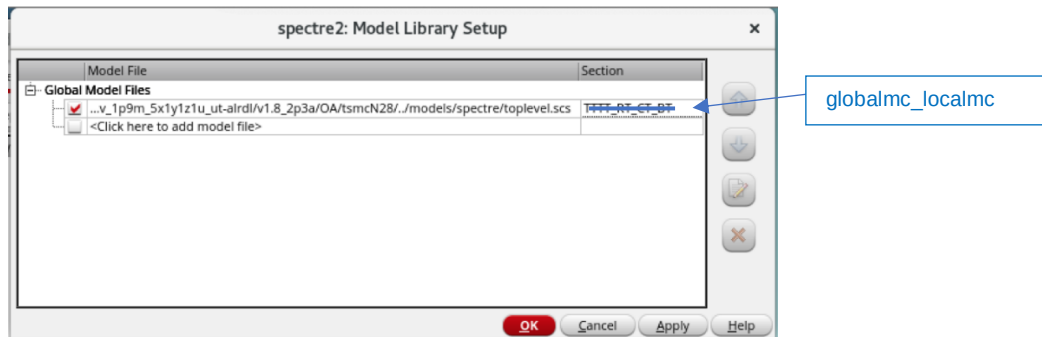


Low-Discrepancy Sequence ensures a better distribution of devices variations across all possible range compared with pure random sequence, which makes it possible to obtain more accurate statistic results with less number of points when compared with pure random sequence. See examples below with the 3 methods for 256 points (source Cadence Community website):



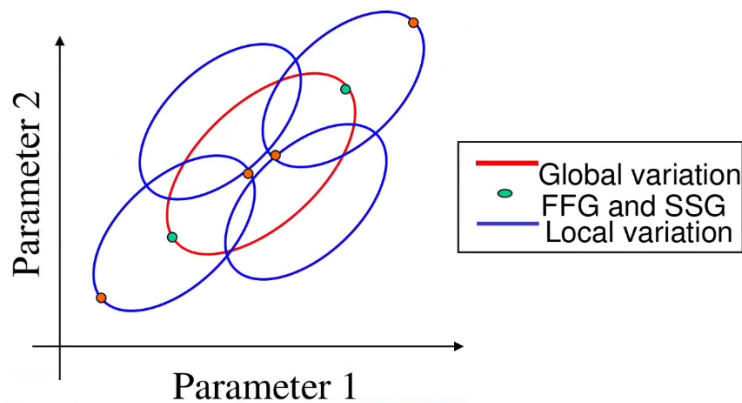
6.2. Monte-Carlo Model Libraries files

On “Model Library Setup” dialog box, select the “globalmc_localmc” section. Since only “mismatch” is selected just local mismatch will be run with typical process corner.



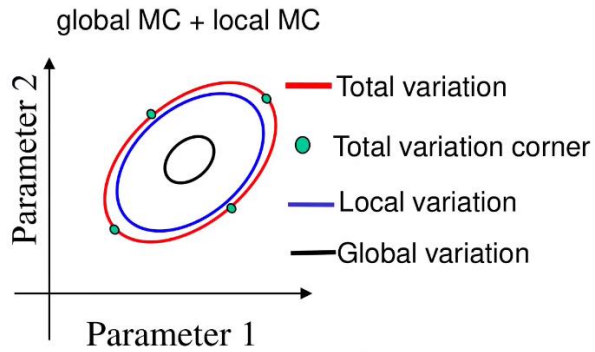
From TSMC “Model Usage Guide” document is possible to understand the statistical variations associated with each section.

On “SSSS_RS_CS_BS”, “FFFF_RF_CF_BF”, “SFSF_RT_CT_BT” and “FSFS_RT_CT_BT” sections, the local mismatch is added on top of each process corner. These options should be used on very sensitive circuits, where matching between branches is essential, like for example Differential Amplifiers, PLL’s, VCO’s, etc. The plot below is an example of possible statistical variations when “Global Corner + Local Monte-Carlo” sections are selected for simulation.



On “globalmc_localmc” section with Monte-Carlo “All” variations option selected, all devices will have a global variation withing the process statistical distribution plus a local mismatch applied to each device within the mismatch statistical distribution.

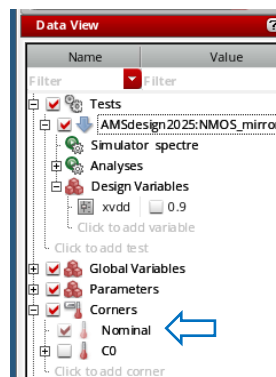
The plot below is an example of possible statistical variations when “Global Monte-Carlo + Local Monte-Carlo” sections are selected for simulation.



$$\sigma_{total}^2 = \sigma_{global}^2 + \sigma_{local}^2$$

6.3. Monte-Carlo Mismatch simulations results

Select just “Nominal” corner and run the simulations.



See example below of measured results summary.

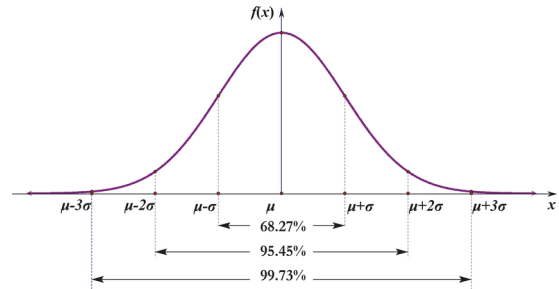
(explore the various formats available of presenting the results)

Outputs Setup Results								
Summary								
Test	Output	Min	Max	Mean	Median	Std Dev	Spec	Pass/Fail
AMSDesign2025:NMOS_mirror:1	Id_MNA	10u	10.01u	10.01u	10.01u	1.79n		
AMSDesign2025:NMOS_mirror:1	Vth_MNA	462.6m	470.9m	467.1m	467.1m	1.504m		
AMSDesign2025:NMOS_mirror:1	Vds_MNA	478.9m	486.8m	483m	483m	1.437m		
AMSDesign2025:NMOS_mirror:1	Vdsat_MNA	94.41m	95.13m	94.77m	94.77m	130.6u		
AMSDesign2025:NMOS_mirror:1	Vsat_marg_MNA	383.9m	392.1m	388.2m	388.3m	1.473m	> 200m	pass
AMSDesign2025:NMOS_mirror:1	OP_region_MNA	2	2	2	2	0		
AMSDesign2025:NMOS_mirror:1	Id_MNB	9.18u	11.14u	9.954u	9.934u	343.4n	range 9u 11u	near
AMSDesign2025:NMOS_mirror:1	Vth_MNB	462.4m	470.9m	467.1m	467.1m	1.516m		
AMSDesign2025:NMOS_mirror:1	Vds_MNB	400m	400m	400m	400m	0		
AMSDesign2025:NMOS_mirror:1	Vdsat_MNB	92.25m	98.56m	94.78m	94.76m	1.166m		
AMSDesign2025:NMOS_mirror:1	Vsat_marg_MNB	301.4m	307.8m	305.2m	305.2m	1.166m	> 200m	pass
AMSDesign2025:NMOS_mirror:1	OP_region_MNB	2	2	2	2	0		
AMSDesign2025:NMOS_mirror:1	Id_MNC	8.92u	11.24u	9.952u	9.949u	346.6n	range 9u 11u	near
AMSDesign2025:NMOS_mirror:1	Vth_MNC	462.8m	471.4m	467.1m	467m	1.536m		
AMSDesign2025:NMOS_mirror:1	Vds_MNC	400m	400m	400m	400m	0		
AMSDesign2025:NMOS_mirror:1	Vdsat_MNC	91.43m	98.72m	94.77m	94.76m	1.184m		
AMSDesign2025:NMOS_mirror:1	Vsat_marg_MNC	301.3m	308.6m	305.2m	305.2m	1.184m	> 200m	pass
AMSDesign2025:NMOS_mirror:1	OP_region_MNC	2	2	2	2	0		
AMSDesign2025:NMOS_mirror:1	Id_MNA_MNC_error	-1.125u	824.6n	52.91n	72.34n	342.1n	range -300n 300n	fail
AMSDesign2025:NMOS_mirror:1	Id_MNA_MNC_error	-1.227u	1.084u	54.4n	56.45n	345.3n	range -300n 300n	fail
AMSDesign2025:NMOS_mirror:1	Id_MNB_MNC_error	-898.6n	1.091u	1.497n	-10.62n	339n	range -300n 300n	fail

On point 5, with just PVT corner variations, the bias currents difference between branch B and C (Id_MNB_MNC_error) was 0 for all corners, because all devices have been affected by the same conditions (global variations). The mismatch between the devices that happens in real silicon (local variations) was not considered. With the addition of mismatch, even with typical PVT conditions, there will be differences in branches B and C currents

For accurate systems the 3σ is used as an accepted variation of a measured value, it means more than 99% of the samples will be within this range value.

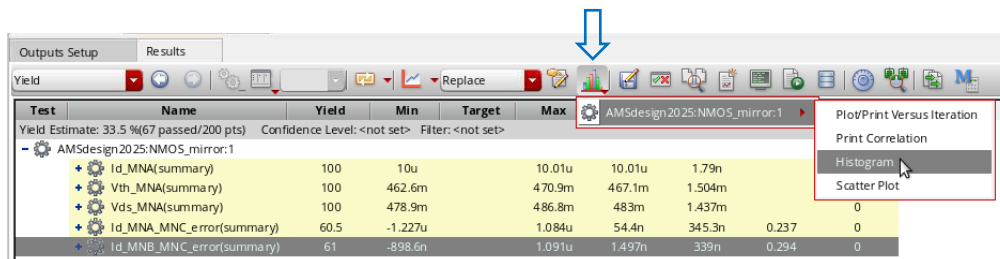
On ADE, we have access to just 1σ variation results (Std Dev). To simplify the calculation of the 3σ usually the 1σ , is multiplied by 3.



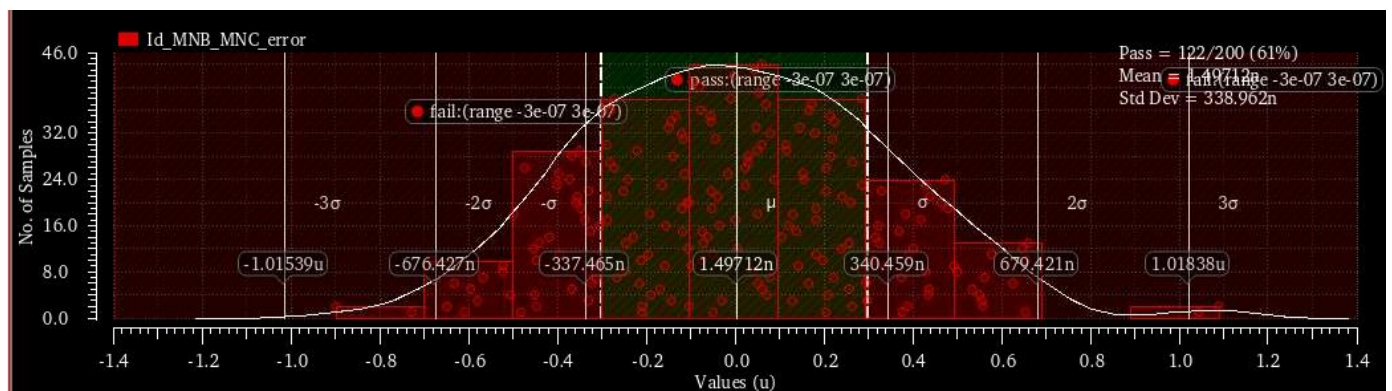
(Source: www.researchgate.net/)

Looking into the Monte-Carlo results, the difference between the drain currents of MNB and MNC (Id_MNB_MNC_error) has a Std Dev (σ) of 339nA and a mean (μ) of 1.497n. Statistically this means that 99.73% of the cases will be within the interval $[\mu - 3\sigma ; \mu + 3\sigma] = [-1.016\mu\text{A} ; 1.018\mu\text{A}]$. Computing this error in percentage referring to the 10uA of the mirror we got [-10.16% ; 10.18%] variation between these two currents, which is higher than $\pm 10\%$.

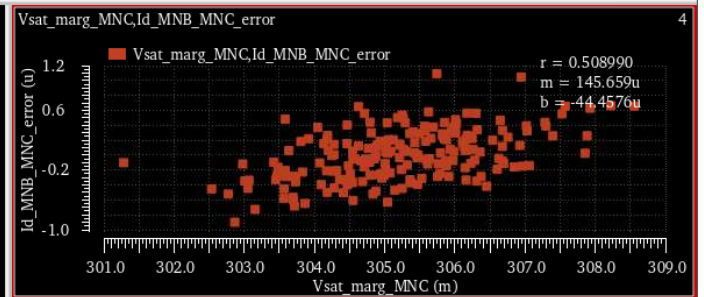
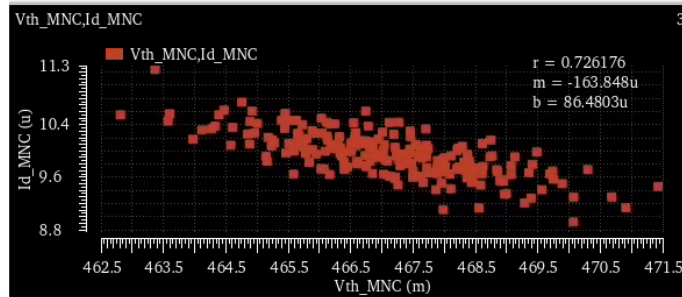
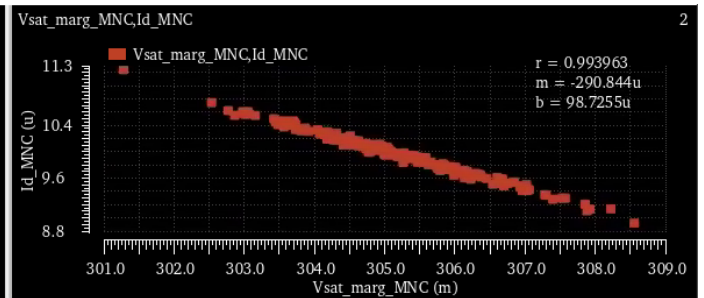
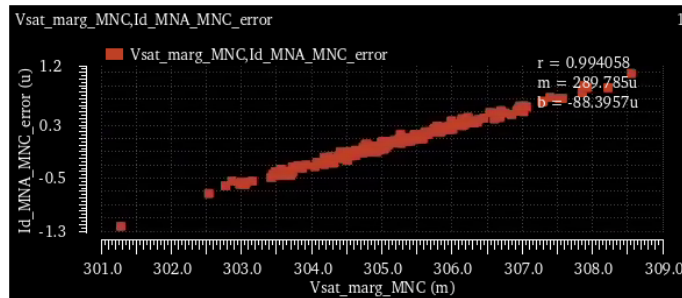
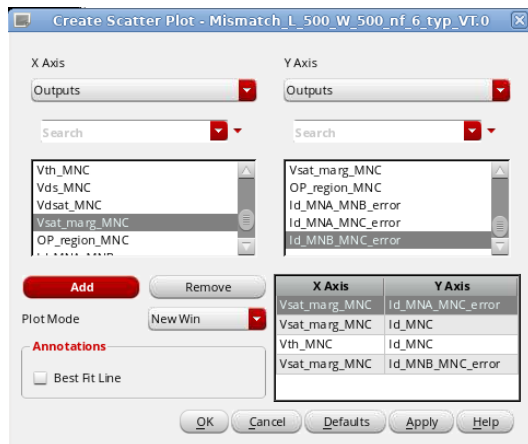
Results can also plot in “Histogram” or “Scatter Plot” formats.



See example of histogram plot below for drain current difference error between transistors MNB and MNC.



The “Scatter Plot” has the possibility to choose the two axis, see examples below.



6.4. Monte-Carlo Process + Mismatch simulations results

Change the Monte-Carlo variation method from “Mismatch” to “All” (Process + Mismatch) and re-run the simulation. See below example of measured results.

Outputs Setup		Results							
Summary									
Test	Output	Min	Max	Mean	Median	Std Dev	Spec	Pass/Fail	
AMSdesign2025:NMOS_mirror:1	Id_MNA	10u	10.02u	10u	10u	5.077n			
AMSdesign2025:NMOS_mirror:1	Vth_MNA	445.5m	485.5m	467.1m	467.1m	7.855m			
AMSdesign2025:NMOS_mirror:1	Vds_MNA	461.6m	500.3m	483m	482.9m	7.703m			
AMSdesign2025:NMOS_mirror:1	Vdsat_MNA	93.14m	96.96m	94.78m	94.73m	724.1u			
AMSdesign2025:NMOS_mirror:1	Vsat_marg_MNA	367.2m	405.9m	388.3m	388.3m	7.774m	> 200m	pass	
AMSdesign2025:NMOS_mirror:1	OP_region_MNA	2	2	2	2	0			
AMSdesign2025:NMOS_mirror:1	Id_MNB	9.131u	10.8u	9.953u	9.953u	340n	range 9u 11u	pass	
AMSdesign2025:NMOS_mirror:1	Vth_MNB	445m	489.2m	467.1m	466.8m	7.786m			
AMSdesign2025:NMOS_mirror:1	Vds_MNB	400m	400m	400m	400m	0			
AMSdesign2025:NMOS_mirror:1	Vdsat_MNB	90.97m	98.12m	94.79m	94.92m	1.314m			
AMSdesign2025:NMOS_mirror:1	Vsat_marg_MNB	301.9m	309m	305.2m	305.1m	1.314m	> 200m	pass	
AMSdesign2025:NMOS_mirror:1	OP_region_MNB	2	2	2	2	0			
AMSdesign2025:NMOS_mirror:1	Id_MNC	9.127u	11.21u	9.958u	9.941u	352.4n	range 9u 11u	near	
AMSdesign2025:NMOS_mirror:1	Vth_MNC	446m	487.5m	467m	467m	7.732m			
AMSdesign2025:NMOS_mirror:1	Vds_MNC	400m	400m	400m	400m	0			
AMSdesign2025:NMOS_mirror:1	Vdsat_MNC	90.87m	98.74m	94.81m	94.86m	1.401m			
AMSdesign2025:NMOS_mirror:1	Vsat_marg_MNC	301.3m	309.1m	305.2m	305.1m	1.401m	> 200m	pass	
AMSdesign2025:NMOS_mirror:1	OP_region_MNC	2	2	2	2	0			
AMSdesign2025:NMOS_mirror:1	Id_MNA_MNB_error	-801.2n	870.2n	51.64n	51.31n	339.5n	range -300n 300n	fail	
AMSdesign2025:NMOS_mirror:1	Id_MNA_MNC_error	-1.213u	872.4n	46.15n	62.59n	352.1n	range -300n 300n	fail	
AMSdesign2025:NMOS_mirror:1	Id_MNB_MNC_error	-1.036u	1.147u	-5.498n	-28.02n	341.1n	range -300n 300n	fail	

Compare the results with the ones having just mismatch variation. What could we conclude?

- The statistical results are not very different.
- This tells us the mismatch is the dominant factor for the current mirroring error A to B and A to C.
- The mismatch is the only factor affecting the difference between currents in branch B and C.
- This was expected, since we have seen that stand-alone PVT variations were not causing any difference between branch B and branch C currents, as the global variations affect similarly branch B and C paired devices.

Monte-Carlo devices parameters variations have a direct relation with the size of the devices. Higher sizes will exhibit lower variations.

To verify the above sentence, try to increase the size of the transistors by 2x. Please note, to maintain the same operating point, the devices need to maintain the same Width/Length ratios.

See example below of measured results summary for bigger devices.

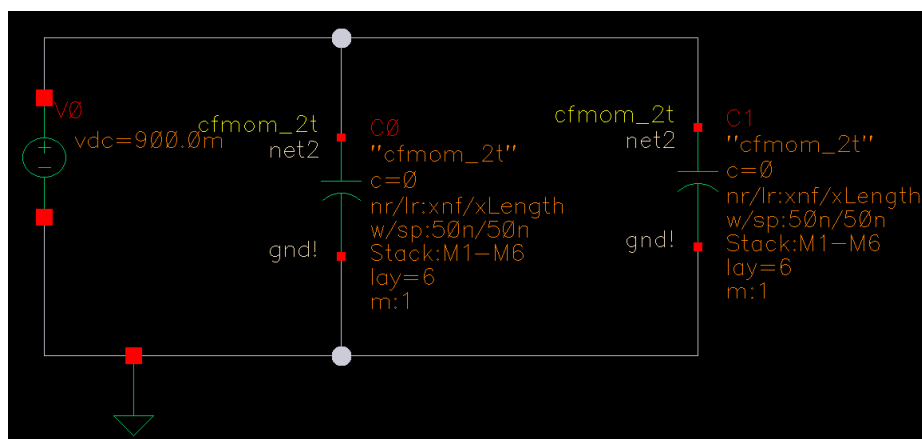
Although the errors between the mirrored currents have not reached the specs, they were significantly reduced with the increase of devices sizes.

Outputs Setup		Results						
Summary		Replace						
Test	Output	Min	Max	Mean	Median	Std. Dev	Spec	Pass/Fail
AMSDesign2025:NMOS_mirror:1	Id_MNA	9.998u	10.02u	10u	10u	5.744n		
AMSDesign2025:NMOS_mirror:1	Vth_MNA	453.3m	494.4m	475.8m	475.5m	7.876m		
AMSDesign2025:NMOS_mirror:1	Vds_MNA	465.6m	504.8m	487.4m	487.4m	7.789m		
AMSDesign2025:NMOS_mirror:1	Vdsat_MNA	92.89m	96.15m	94.3m	94.26m	655.1u		
AMSDesign2025:NMOS_mirror:1	Vsat_marg_MNA	371.4m	411.2m	393.1m	393m	7.807m	> 200m	pass
AMSDesign2025:NMOS_mirror:1	OP_region_MNA	2	2	2	2	0		
AMSDesign2025:NMOS_mirror:1	Id_MNB	9.522u	10.43u	9.98u	9.985u	187.3n	range 9u 11u	pass
AMSDesign2025:NMOS_mirror:1	Vth_MNB	453m	496.3m	475.8m	475.6m	7.837m		
AMSDesign2025:NMOS_mirror:1	Vds_MNB	400m	400m	400m	400m	0		
AMSDesign2025:NMOS_mirror:1	Vdsat_MNB	91.94m	96.65m	94.31m	94.32m	865.3u		
AMSDesign2025:NMOS_mirror:1	Vsat_marg_MNB	303.3m	308.1m	305.7m	305.7m	865.3u	> 200m	pass
AMSDesign2025:NMOS_mirror:1	OP_region_MNB	2	2	2	2	0		
AMSDesign2025:NMOS_mirror:1	Id_MNC	9.514u	10.65u	9.982u	9.971u	194.4n	range 9u 11u	pass
AMSDesign2025:NMOS_mirror:1	Vth_MNC	453.6m	495.5m	475.8m	475.5m	7.807m		
AMSDesign2025:NMOS_mirror:1	Vds_MNC	400m	400m	400m	400m	0		
AMSDesign2025:NMOS_mirror:1	Vdsat_MNC	91.82m	96.5m	94.32m	94.32m	922.6u		
AMSDesign2025:NMOS_mirror:1	Vsat_marg_MNC	303.5m	308.2m	305.7m	305.7m	922.6u	> 200m	pass
AMSDesign2025:NMOS_mirror:1	OP_region_MNC	2	2	2	2	0		
AMSDesign2025:NMOS_mirror:1	Id_MNA_MNB_error	-433.9n	482.6n	24.26n	18.13n	187n	range -300n 300n	fail
AMSDesign2025:NMOS_mirror:1	Id_MNA_MNC_error	-652.8n	485n	21.26n	30.2n	194.4n	range -300n 300n	fail
AMSDesign2025:NMOS_mirror:1	Id_MNB_MNC_error	-568.2n	623.6n	-2.992n	-7.188n	188.1n	range -300n 300n	fail

7. Capacitor's Mismatch

7.1. schematic

Create a new schematic and instance 2 Metal-oxide-Metal (MOM) capacitors from TSMC28 PDK technology and connect them to a voltage source with 0.9V DC voltage value. Give variable names to the number of fingers (eg. xnf) and Length of each finger (eg. xLength). See example below.



Library Name	tsmc28
Cell Name	cfmom_2t
View Name	symbol
Instance Name	C0

CDF Parameter	Value
Model name	cfmom_2t
description	CFMOM_2T
fingers Width(M)	50n M
fingers Space(M)	50n M
fingers Length(M)	xLength M
Number of fingers	xnf
FMOM Bottom Metal Layer	1
FMOM Top Metal Layer	6

7.2. Create a Maestro ADE and run process corner simulations

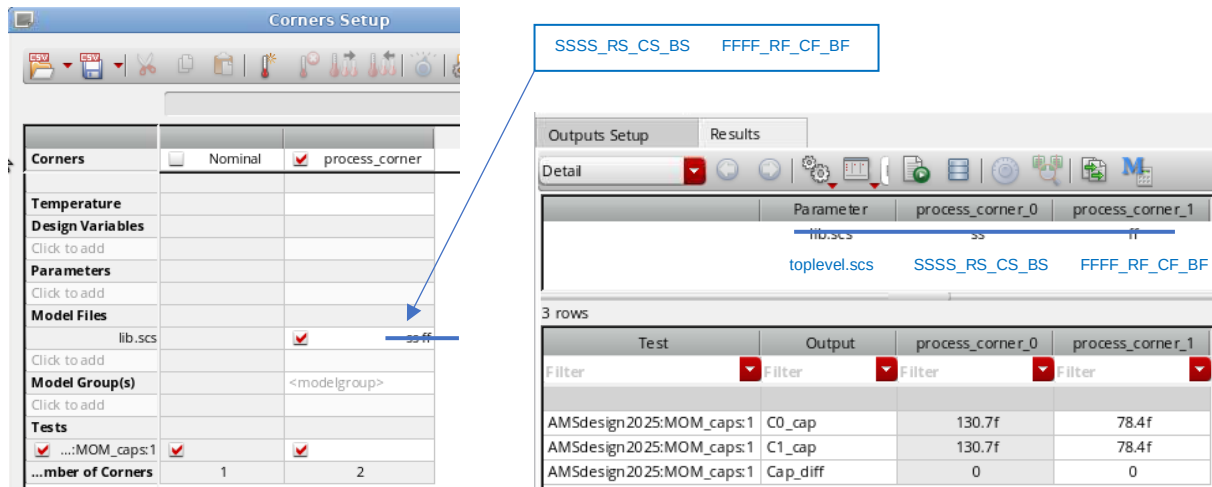
Create a new Maestro ADE. Select DC analyses. Run a typical process (section "TTTT_RT_CT_BT") and temperature (27°C) and save the capacitors values from "dcOpInfo" simulation to ADE (if necessary, revisit point 3.6 above on how to add expressions to ADE). See example below:

Test	Name	Type	Details	EvalType	Plot
AMSDesign2025:MOM_caps:1	C0_cap	expr	pv("C0.cab" "cap" ?result "dcOpInfo")	point	✓
AMSDesign2025:MOM_caps:1	C1_cap	expr	pv("C1.cab" "cap" ?result "dcOpInfo")	point	✓
AMSDesign2025:MOM_caps:1	Cap_diff	expr	(C0_cap - C1_cap)	point	✓

Refresh results tab to see capacitors values. See example below:

Test	Output	Nominal
AMSDesign2025:MOM_caps:1	C0_cap	104.5f
AMSDesign2025:MOM_caps:1	C1_cap	104.5f
AMSDesign2025:MOM_caps:1	Cap_diff	0

Add “SSSS_RS_CS_BS” and “FFFF_RF_CF_BF” process corner variations and run the simulations.



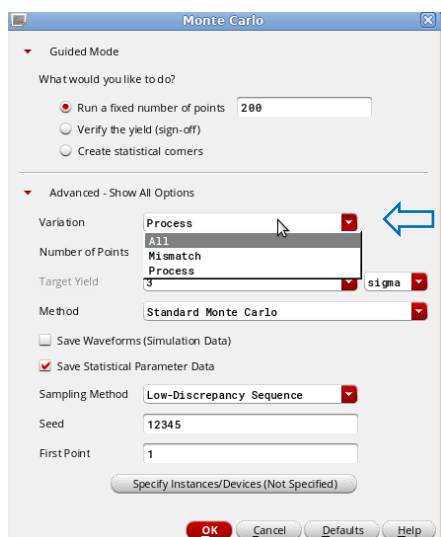
Compare the capacitors values for the different process corners.

- A total balanced variation of $\pm 25\%$ is observed.

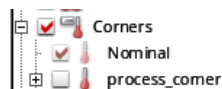
As expected, there is no difference between their values because mismatch variation has not been added.

7.3. Run Monte-Carlo variation corners

Select Monte-Carlo simulation. On model's library configuration dialog box select “globalmc_localmc” section with 200 simulation points and run 3 simulations each one with a different type of variation (“Process”, “Mismatch” and “All”).



Select just Nominal corner:



See examples below of simulation results for the 3 different types of Monte-Carlo variations.

- “globalmc_localmc” section with global “Process” variation:

Test	Name	Yield	Min	Target	Max	Mean	Std Dev
Yield Estimate: 100 %(200 passed/200 pts) Confidence Level: <not set> Filter: <not set>							
-	AMSdesign2025:MOM_caps:1						
+	C0_cap(summary)	100	81.15f		134.2f	104.6f	8.779f
+	C1_cap(summary)	100	81.15f		134.2f	104.6f	8.779f
+	Cap_diff(summary)	100	0		0	0	0

- “globalmc_localmc” section with local “Mismatch” variation:

Test	Name	Yield	Min	Target	Max	Mean	Std Dev
Yield Estimate: 100 %(200 passed/200 pts) Confidence Level: <not set> Filter: <not set>							
-	AMSdesign2025:MOM_caps:1						
+	C0_cap(summary)	100	104.3f		104.7f	104.5f	73.12a
+	C1_cap(summary)	100	104.3f		104.7f	104.5f	73.36a
+	Cap_diff(summary)	100	-382.7a		256.7a	-1.651a	108a

- “globalmc_localmc” section with “All” (global Process + local Mismatch) variation:

Test	Name	Yield	Min	Target	Max	Mean	Std Dev
Yield Estimate: 100 %(200 passed/200 pts) Confidence Level: <not set> Filter: <not set>							
-	AMSdesign2025:MOM_caps:1						
+	C0_cap(summary)	100	81.24f		134.2f	104.6f	8.777f
+	C1_cap(summary)	100	81.25f		134.2f	104.6f	8.776f
+	Cap_diff(summary)	100	-356.4a		260.7a	-1.216a	103.2a

Compare the results and conclude the impact of global Process and local Mismatch variations on capacitors' values.

For total corner variations the foundry uses the 3σ results. See calculations below for above simulation results.

$$[\mu - 3\sigma; \mu + 3\sigma] = [104.6 - (3 \times 8.777); 104.6 + (3 \times 8.777)] \text{ fF} = [78.27; 130.93] \text{ fF}$$

Let's compare them with the total corner variations results obtained earlier:

$$[\text{ff}; \text{tt}; \text{ss}] = [78.4; 104.5; 130.7] \text{ fF}$$

Change the model's sections to "SSSS_RS_CS_BS" and "FFFF_RF_CF_BF" and compare with the results above with "globalmc_localmc". See below example of simulation results.

- "SSSS_RS_CS_BS" section with "Mismatch" variation (SS Process + local Mismatch):

Test	Name	Yield	Min	Target	Max	Mean	Std Dev
Yield Estimate: 100 %(200 passed/200 pts) Confidence Level: <not set> Filter: <not set>							
- AMSdesign2025:MOM_caps:1							
+ C0_cap(summary)		100	130.4f		130.9f	130.7f	91.1a
+ C1_cap(summary)		100	130.4f		130.9f	130.7f	89.58a
+ Cap_diff(summary)		100	-285a		331.7a	346.2z	123.6a

Note the results are centered on "SSSS_RS_CS_BS" process corner result (130.7fF) obtained on point 7.2.

- "FFFF_RF_CF_BF" section with "Mismatch" variation (FF Process + local Mismatch):

Test	Name	Yield	Min	Target	Max	Mean	Std Dev
Yield Estimate: 100 %(200 passed/200 pts) Confidence Level: <not set> Filter: <not set>							
- AMSdesign2025:MOM_caps:1							
+ C0_cap(summary)		100	78.24f		78.56f	78.4f	54.66a
+ C1_cap(summary)		100	78.25f		78.54f	78.4f	53.75a
+ Cap_diff(summary)		100	-171a		199a	207.7z	74.14a

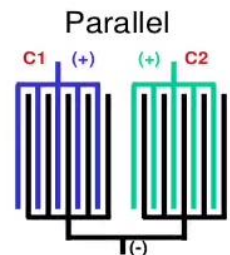
Note the results are centered on "FFFF_RF_CF_BF" process corner result (130.7fF) obtained on point 7.2.

7.4. Calculation of capacitor's matching parameter (Ac)

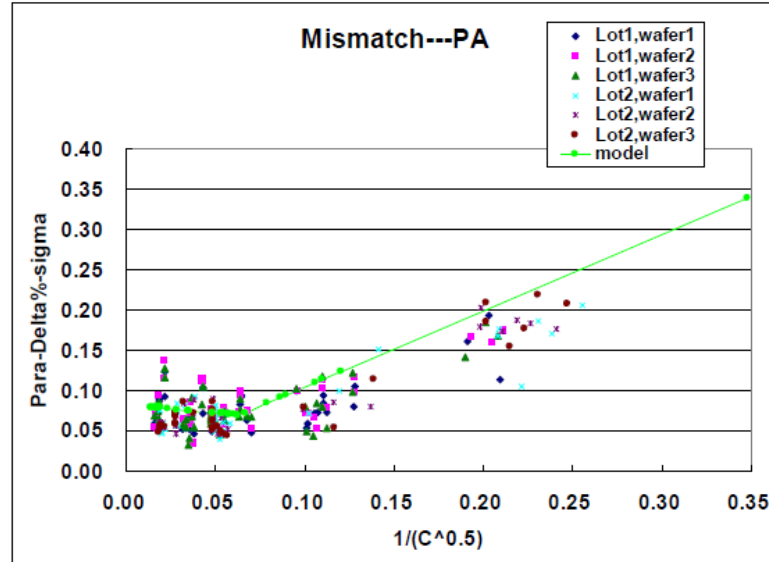
The capacitors mismatch has been modeled on the PDK spectre files with an Ac parameter according to the following formula.

$$\sigma\left(\frac{\Delta C}{C}\right) = \frac{Ac}{\sqrt{C}} \quad [\%]$$

The Ac parameter was obtained on the foundry from silicon measurements of the difference between 2 parallel MOM devices capacitance values.



On the graphic below, present on TSMC devices mismatch information document, it is possible to see the 1 sigma statistical calculation percentage of the variation between 2 parallel capacitors values.



The A_c parameter will correspond to the slope of the linear regression (green line) calculated from the silicon results for different wafers.

Choosing two different capacitors sizes, for example 25fF ($\frac{1}{\sqrt{25}} = 0.2 fF^{-0.5}$) and 100fF ($\frac{1}{\sqrt{100}} = 0.1 fF^{-0.5}$) is possible to calculate the A_c .

$$A_c = \frac{0.2 - 0.1}{0.2 - 0.1} = 1 \quad [\% \cdot fF^{-0.5}]$$

The “ A_c ” parameter can be used on the modeling of the DAC capacitors mismatch variation (for example in an ADC Matlab behavior modelling script). The results can then be used on the definition of the DAC capacitors calibration corrections factors for a good ADC DNL/INL linearity.

The standard variation of the difference between the 2 random capacitors values is given by:

$$\sigma(\Delta c) = \sigma(c_1 - c_2) = \sqrt{\sigma^2(c_1) + \sigma^2(c_2) + cov(c_1, c_2)}$$

Assuming the standard variations values of c_1 and c_2 are independent, the covariance is canceled.

$$\sigma(\Delta c) = \sqrt{\sigma^2(c_1) + \sigma^2(c_2)} = \sqrt{2 \cdot \sigma_n^2} = \sqrt{2} \cdot \sigma_n$$

Dividing by normalized capacitor value C_n is possible to obtain the variation of a capacitor value from the A_c and respective capacitor mean value:

$$\sigma\left(\frac{\Delta c}{C}\right) = \sqrt{2} \cdot \frac{\sigma_n}{C_n} \Leftrightarrow \frac{\sigma_n}{C_n} = \sigma\left(\frac{\Delta c}{C}\right) \cdot \frac{1}{\sqrt{2}} \Leftrightarrow \frac{\sigma_n}{C_n} = \frac{A_c}{\sqrt{C_n}} \cdot \frac{1}{\sqrt{2}} \Leftrightarrow \sigma_n = \frac{A_c}{\sqrt{C_n}} \cdot \frac{1}{\sqrt{2}} \cdot C_n$$

With the above formula it is possible to obtain an estimation of the standard deviation for the capacitor value:

$$\sigma_{(104.5fF)} = \frac{0.01}{\sqrt{104.5}} \cdot \frac{1}{\sqrt{2}} \cdot 104.5 = 0.0723 fF$$

As can be seen from the table below, the resulting value is similar with the standard deviation obtained from Monte-Carlo local “Mismatch” simulation (obtained on point 7.3 simulations above). See respective simulation results below:

Outputs Setup		Results					
Yield							
Test	Name	Yield	Min	Target	Max	Mean	Std Dev
Yield Estimate: 100 %(200 passed/200 pts) Confidence Level: <not set> Filter: <not set>							
- AMSdesign2025:MOM_caps:1							
+ C0_cap(summary)		100	104.3f		104.7f	104.5f	73.12a
+ C1_cap(summary)		100	104.3f		104.7f	104.5f	73.36a
+ Cap_diff(summary)		100	-382.7a		256.7a	-1.651a	108a

Monte-Carlo simulation results with “globalmc_localmc” section and local “Mismatch” variation.

(xnf=20 ; xLength=10u)

In case the access to foundry documentation is not possible, the Ac parameter can be obtained from Monte-Carlo local mismatch simulation results.

Let's consider the Monte-Carlo local “Mismatch” simulation results above.

$$Ac = \sigma \left(\frac{\Delta c}{C} \right) \cdot \sqrt{C} = \frac{0.108}{104.5} \cdot \sqrt{104.5} = 1.06 \quad [\% \cdot fF^{-0.5}]$$

The Ac results match with the value taken from TSMC documentation plot.

Re-running the Monte-Carlo with smaller capacitors sizes. From example below with xnf=10 and xLength=5u, it is possible to see the Ac parameter has not changed significantly, which indicates we can use the Ac parameter independent from the unit capacitor size/value to estimate the mismatch between 2 distinct capacitors.

Outputs Setup		Results					
Yield							
Test	Name	Yield	Min	Target	Max	Mean	Std Dev
Yield Estimate: 100 %(200 passed/200 pts) Confidence Level: <not set> Filter: <not set>							
- AMSdesign2025:MOM_caps:1							
+ C0_cap(summary)		100	24.63f		24.83f	24.73f	33.98a
+ C1_cap(summary)		100	24.64f		24.83f	24.73f	34.09a
+ Cap_diff(summary)		100	-177.8a		119.3a	-766.9z	50.17a

Monte-Carlo simulation results with “TTTT_RT_CT_BT” section and local “Mismatch” variation.

(xnf=10 ; xLength=5u)

$$Ac = \sigma \left(\frac{\Delta c}{C} \right) \cdot \sqrt{C} = \frac{0.05017}{24.73} \cdot \sqrt{24.73} = 1.01 \quad [\% \cdot fF^{-0.5}]$$

The calculation of the capacitor value standard deviation from the Ac value, for the smaller sized capacitor, can also be confirmed to match with simulation results:

$$\sigma_{(24.73fF)} = \frac{0.01}{\sqrt{24.73}} \cdot \frac{1}{\sqrt{2}} \cdot 24.73 = 0.0352 fF$$

A stable A_c is inline with the expectation that a smaller sized capacitor will have a higher mismatch value between 2 parallel structures. From the formula it can be seen the sigma (σ) has an inverse relation with the $\sqrt{C}$.

From the examples above, it can be seen, the mismatch is 2 times bigger for the smaller sized capacitors when compared with the mismatch between the two bigger capacitors.

$$\frac{c(3\sigma)}{C_{\text{Bigger Size}}} = \frac{3 \times 0.07312fF}{104.5fF} = 0.21 \text{ [\%]} \quad ; \quad \frac{c(3\sigma)}{C_{\text{Smaller Size}}} = \frac{3 \times 0.03398fF}{24.73fF} = 0.41 \text{ [\%]}$$

7.5. How to save data in Monte-Carlo simulation

By default, the Monte-Carlo simulation does not save the simulation data to reduce disk space usage. Without saving them it is not possible to plot signals or run new post simulation calculations.

To be able to save the data on Monte-Carlo simulations, open respective configuration dialog box and select “Save Waveforms (Simulation Data)”.

